

Important notice

Dear Customer,

On 7 February 2017 the former NXP Standard Product business became a new company with the tradename **Nexperia**. Nexperia is an industry leading supplier of Discrete, Logic and PowerMOS semiconductors with its focus on the automotive, industrial, computing, consumer and wearable application markets

In data sheets and application notes which still contain NXP or Philips Semiconductors references, use the references to Nexperia, as shown below.

Instead of <http://www.nxp.com>, <http://www.philips.com/> or <http://www.semiconductors.philips.com/>, use **<http://www.nexperia.com>**

Instead of sales.addresses@www.nxp.com or sales.addresses@www.semiconductors.philips.com, use **salesaddresses@nexperia.com** (email)

Replace the copyright notice at the bottom of each page or elsewhere in the document, depending on the version, as shown below:

- © NXP N.V. (year). All rights reserved or © Koninklijke Philips Electronics N.V. (year). All rights reserved

Should be replaced with:

- © **Nexperia B.V. (year). All rights reserved.**

If you have any questions related to the data sheet, please contact our nearest sales office via e-mail or telephone (details via **salesaddresses@nexperia.com**). Thank you for your cooperation and understanding,

Kind regards,

Team Nexperia

TJA1080

FlexRay transceiver

Rev. 02 — 12 July 2007

Product data sheet

1. General description

The TJA1080 is a FlexRay transceiver, which is in line with the FlexRay electrical physical layer specification V2.1 Rev. A (see [Ref. 1](#)). It is primarily intended for communication systems from 1 Mbit/s to 10 Mbit/s, and provides an advanced interface between the protocol controller and the physical bus in a FlexRay network.

The TJA1080 can be configured to be used as an active star transceiver or as a node transceiver.

The TJA1080 provides differential transmit capability to the network and differential receive capability to the FlexRay controller. It offers excellent EMC performance as well as high ESD protection.

The TJA1080 actively monitors the system performance using dedicated error and status information (readable by any microcontroller), as well as internal voltage and temperature monitoring.

The TJA1080 supports the mode control as used in NXP Semiconductors TJA1054 (see [Ref. 2](#)) and TJA1041 (see [Ref. 3](#)) CAN transceivers.

2. Features

2.1 Optimized for time triggered communication systems

- Data transfer up to 10 Mbit/s
- Usable for 14 V and 42 V powered systems
- Very low ElectroMagnetic Emission (EME) to support unshielded cable
- Differential receiver with high common-mode range for ElectroMagnetic Immunity (EMI)
- Transceiver can be used for linear passive bus topologies as well as active star topologies
- Auto I/O level adaptation to host controller supply voltage V_{IO}
- Bus guardian interface included
- Automotive product qualification in accordance with AEC-Q100

2.2 Low power management

- Low power management including two inhibit switches
- Very low current in Sleep and Standby mode
- Wake-up via wake-up symbol on the bus lines (remote), negative edge on pin WAKE (local), and a positive edge on pin STBN if V_{IO} is present
- Wake-up source recognition
- Automatic power-down (in Star-sleep mode) in star configuration

2.3 Diagnosis (detection and signalling)

- Overtemperature detection
- Short-circuit on bus lines
- V_{BAT} power-on flag (first battery connection and cold start)
- Pin TXEN and pin BGE clamping
- Undervoltage detection on pins V_{BAT} , V_{CC} and V_{IO}
- Wake source indication

2.4 Protections

- Bus pins protected against 8 kV HBM ESD pulses
- Bus pins protected against transients in automotive environment (ISO 7637 class C compliant)
- Bus pins short-circuit proof to battery voltage (14 V and 42 V) and ground
- Fail-safe mode in case of an undervoltage on pins V_{BAT} , V_{CC} or V_{IO}
- Passive behavior of bus lines in the event that transceiver is not powered

3. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{BAT}	supply voltage on pin V_{BAT}	no time limit	-0.3	-	+60	V
		operating range	6.5	-	60	V
V_{CC}	supply voltage	no time limit	-0.3	-	+5.5	V
		operating range	4.75	-	5.25	V
V_{BUF}	supply voltage on pin V_{BUF}	no time limit	-0.3	-	+5.5	V
		operating range	4.75	-	5.25	V
V_{IO}	supply voltage on pin V_{IO}	no time limit	-0.3	-	+5.5	V
		operating range	2.2	-	5.25	V
V_{TRXD0}	voltage on pin TRXD0		-0.3	-	+5.5	V
V_{TRXD1}	voltage on pin TRXD1		-0.3	-	+5.5	V
V_{BP}	voltage on pin BP		-60	-	+60	V
V_{BM}	voltage on pin BM		-60	-	+60	V
I_{BAT}	supply current on pin V_{BAT}	low power modes in node configuration	-	-	50	μ A
		normal power modes	-	-	1	mA

Table 1. Quick reference data ...continued

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
I_{CC}	supply current	low power modes	-1	0	+5	μA
		Normal mode; $V_{BGE} = 0 V$; $V_{TXEN} = V_{IO}$; Receive-only mode; Star-idle mode	-	-	15	mA
		Normal mode; $V_{BGE} = V_{IO}$; $V_{TXEN} = 0 V$; V_{BUF} open	[1] -	-	35	mA
		Normal mode; $V_{BGE} = V_{IO}$; $V_{TXEN} = 0 V$; $R_{bus} = \infty \Omega$	-	-	15	mA
		Star-transmit mode	-	-	62	mA
		Star-receive mode	-	-	42	mA
I_{IO}	supply current on pin V_{IO}	low power modes	-1	+1	+5	μA
		Normal and Receive-only mode; $V_{TXD} = V_{IO}$	-	-	1000	μA
$V_{OH(dif)}$	differential HIGH-level output voltage	on pins BP and BM; $40 \Omega < R_{bus} < 55 \Omega$; $V_{CC} = V_{BUF} = 5 V$	600	800	1200	mV
$V_{OL(dif)}$	differential LOW-level output voltage	on pins BP and BM; $40 \Omega < R_{bus} < 55 \Omega$; $V_{CC} = V_{BUF} = 5 V$	-1200	-800	-600	mV
$V_{IH(dif)}$	differential HIGH-level input voltage	on pins BP and BM; normal power modes; $-10 V < V_{BP} < +15 V$; $-10 V < V_{BM} < +15 V$	150	225	300	mV
$V_{IL(dif)}$	differential LOW-level input voltage	on pins BP and BM; normal power modes; $-10 V < V_{BP} < +15 V$; $-10 V < V_{BM} < +15 V$	-300	-225	-150	mV
T_{vj}	virtual junction temperature		[2] -40	-	+150	$^{\circ}C$

[1] Current flows from V_{CC} to V_{BUF} . This means that the maximum sum current $I_{CC} + I_{BUF}$ is 35 mA.

[2] In accordance with IEC 60747-1. An alternative definition of virtual junction temperature T_{vj} is: $T_{vj} = T_{amb} + TD \times R_{th(j-a)}$, where $R_{th(j-a)}$ is a fixed value to be used for the calculation of T_{vj} . The rating for T_{vj} limits the allowable combinations of power dissipation (P) and ambient temperature (T_{amb}).

4. Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
TJA1080TS	SSOP20	plastic shrink small outline package; 20 leads; body with 5.3 mm	SOT339-1
TJA1080TS/N			

5. Block diagram

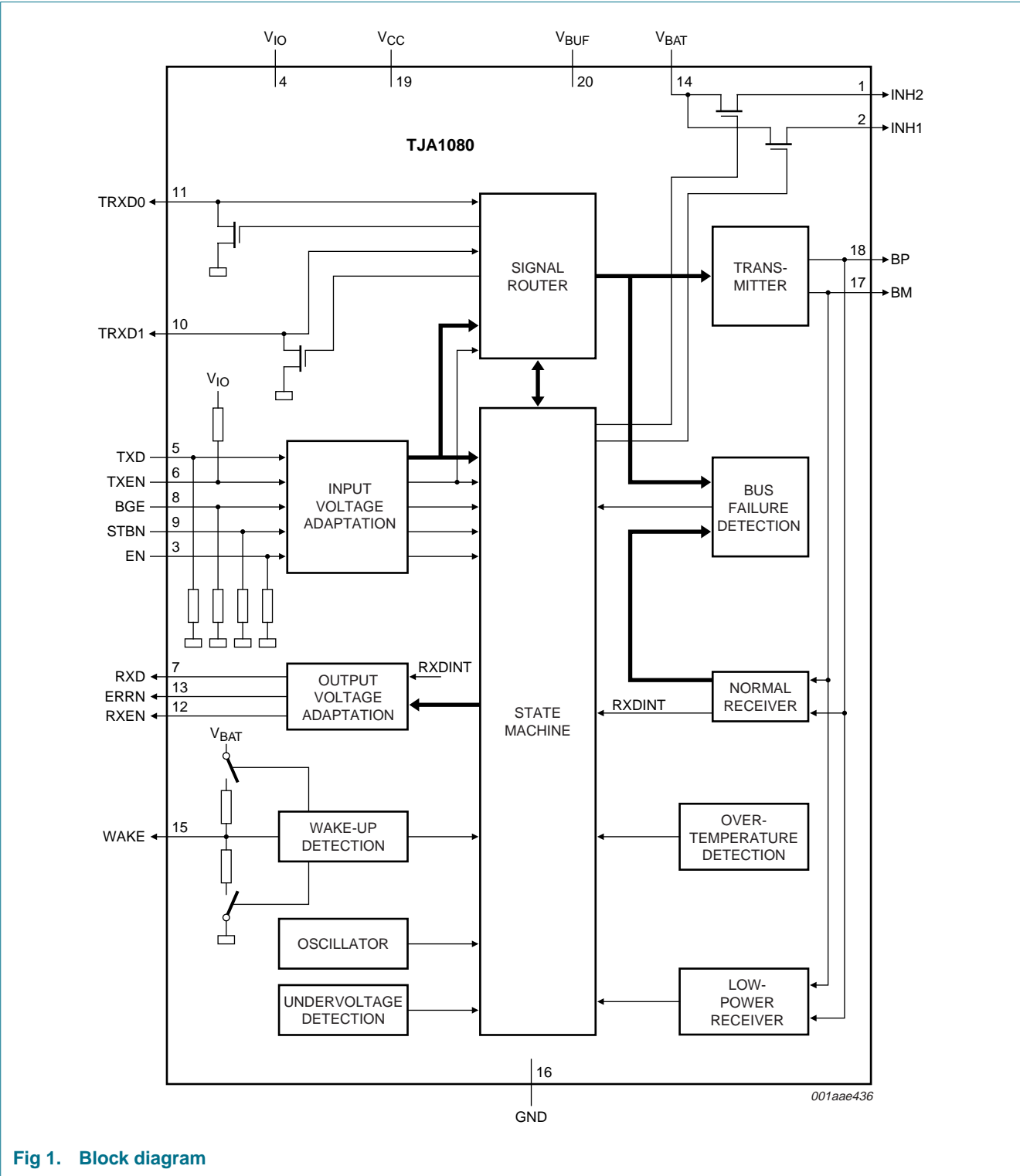


Fig 1. Block diagram

6. Pinning information

6.1 Pinning

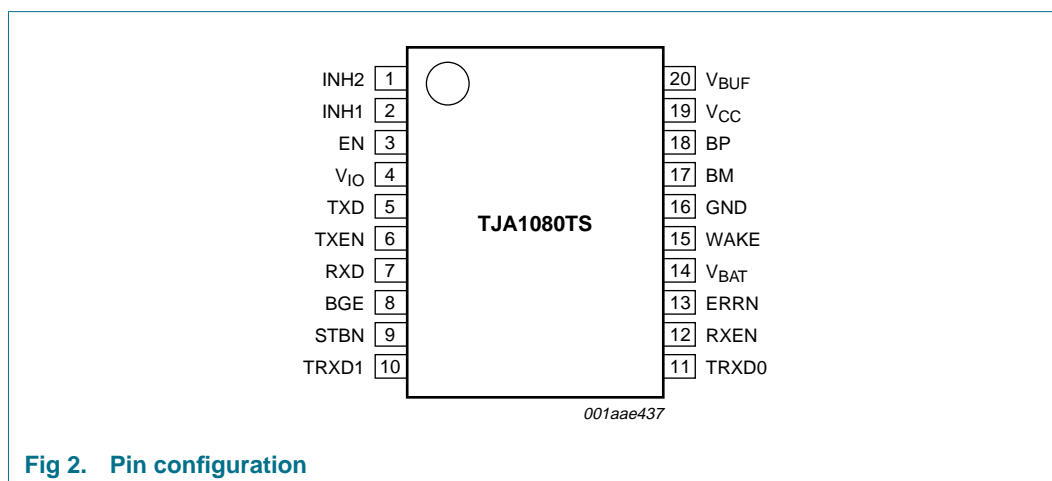


Fig 2. Pin configuration

6.2 Pin description

Table 3. Pin description

Symbol	Pin	Type	Description
INH2	1	O	inhibit 2 output for switching external voltage regulator
INH1	2	O	inhibit 1 output for switching external voltage regulator
EN	3	I	enable input; when HIGH enabled; internal pull-down
V _{IO}	4	P	supply voltage for V _{IO} voltage level adaptation
TXD	5	I	transmit data input; internal pull-down
TXEN	6	I	transmitter enable input; when HIGH transmitter disabled; internal pull-up
RXD	7	O	receive data output
BGE	8	I	bus guardian enable input; when LOW transmitter disabled; internal pull-down
STBN	9	I	standby input; when LOW low power mode; internal pull-down
TRXD1	10	I/O	data bus line 1 for inner star connection
TRXD0	11	I/O	data bus line 0 for inner star connection
RXEN	12	O	receive data enable output; when LOW bus activity detected
ERRN	13	O	error diagnoses output; when LOW error detected
V _{BAT}	14	P	battery supply voltage
WAKE	15	I	local wake-up input; internal pull-up or pull-down (depends on voltage at pin WAKE)
GND	16	P	ground
BM	17	I/O	bus line minus
BP	18	I/O	bus line plus
V _{CC}	19	P	supply voltage (+5 V)
V _{BUF}	20	P	buffer supply voltage

7. Functional description

The block diagram of the total transceiver is illustrated in [Figure 1](#).

7.1 Operating configurations

7.1.1 Node configuration

In node configuration the transceiver operates as a stand-alone transceiver.

The transceiver can be configured as node by connecting pins TRXD0 and TRXD1 to ground during a power-on situation (PWON flag is set). The configuration will be latched when the PWON flag is reset, see [Section 7.7.4 "Power-on flag"](#).

The following operating modes are selectable:

- Normal (normal power mode)
- Receive-only (normal power mode)
- Standby (low power mode)
- Go-to-sleep (low power mode)
- Sleep (low power mode)

7.1.2 Star configuration

In star configuration the transceiver operates as a branch of a FlexRay active star.

The transceiver can be configured as star by connecting pin TRXD0 or TRXD1 to V_{BUF} during a PWON situation (PWON flag is set). The configuration will be latched when the PWON flag is reset, see [Section 7.7.4 "Power-on flag"](#).

It is possible to redirect data from one branch to other branches via the inner bus. It is also possible to send data to all branches via pin TXD, if pins TXEN and BGE have the correct polarity.

The following operating modes are available:

- Star-idle (normal power mode)
- Star-transmit (normal power mode)
- Star-receive (normal power mode)
- Star-sleep (low power mode)
- Star-standby (low power mode)
- Star-locked (normal power mode)

In the star configuration all modes are autonomously controlled by the transceiver, except in the case of a wake-up.

7.1.3 Bus activity and idle detection

The following mechanisms for activity and idle detection are valid for node and star configurations in normal power modes:

- If the absolute differential voltage on the bus lines is higher than $|V_{i(dif)det(act)}|$ for $t_{det(act)(bus)}$, then activity is detected on the bus lines and pin RXEN is switched to LOW which results in pin RXD being released:
 - If, after bus activity detection, the differential voltage on the bus lines is higher than $V_{IH(dif)}$, pin RXD will go HIGH
 - If, after bus activity detection, the differential voltage on the bus lines is lower than $V_{IL(dif)}$, pin RXD will go LOW
- If the absolute differential voltage on the bus lines is lower than $|V_{i(dif)det(act)}|$ for $t_{det(idle)(bus)}$, then idle is detected on the bus lines and pin RXEN is switched to HIGH. This results in pin RXD being blocked (pin RXD is switched to HIGH or stays HIGH)

Additionally, in star configuration, activity and idle can be detected (see [Figure 5](#) for state transitions due to activity/idle detection in star configuration):

- If pin TXEN is LOW for longer than $t_{det(act)(TXEN)}$, activity is detected on pin TXEN
- If pin TXEN is HIGH for longer than $t_{det(idle)(TXEN)}$, idle is detected on pin TXEN
- If pin TRXD0 or TRXD1 is LOW for longer than $t_{det(act)(TRXD)}$, activity is detected on pins TRXD0 and TRXD1
- If pin TRXD0 and TRXD1 is HIGH for longer than $t_{det(idle)(TRXD)}$, idle is detected on pins TRXD0 and TRXD1

7.2 Operating modes in node configuration

The TJA1080 provides two control pins STBN and EN in order to select one of the modes of operation in node configuration. See [Table 4](#) for a detailed description of the pin signalling in node configuration, and [Figure 3](#) for the timing diagram.

All modes are directly controlled via pins EN and STBN unless an undervoltage situation is present.

If V_{IO} and (V_{BUF} or V_{BAT}) are within their operating range, pin ERRN indicates error flag.

Table 4. Pin signalling in node configuration

Mode	STBN	EN	ERRN ^[1]		RXEN		RXD		Transmitter	INH1	INH2
			LOW	HIGH	LOW	HIGH	LOW	HIGH			
Normal	HIGH	HIGH	error flag set	error flag reset	bus activity	bus idle	bus DATA_0	bus DATA_1 or idle	enabled	HIGH	HIGH
Receive-only	HIGH	LOW							disabled		
Go-to-sleep	LOW	HIGH	error flag set ^[2]	error flag reset	wake flag set ^[2]	wake flag reset	wake flag set ^[3]	wake flag reset			float ^[4]
Standby	LOW	LOW									
Sleep	LOW	X								float	float

[1] Pin ERRN provides a serial interface for retrieving diagnostic information.

[2] Valid if V_{IO} and V_{BUF} or V_{BAT} are present.

[3] Valid if V_{IO} and V_{BUF} are present.

[4] If wake flag is not set.

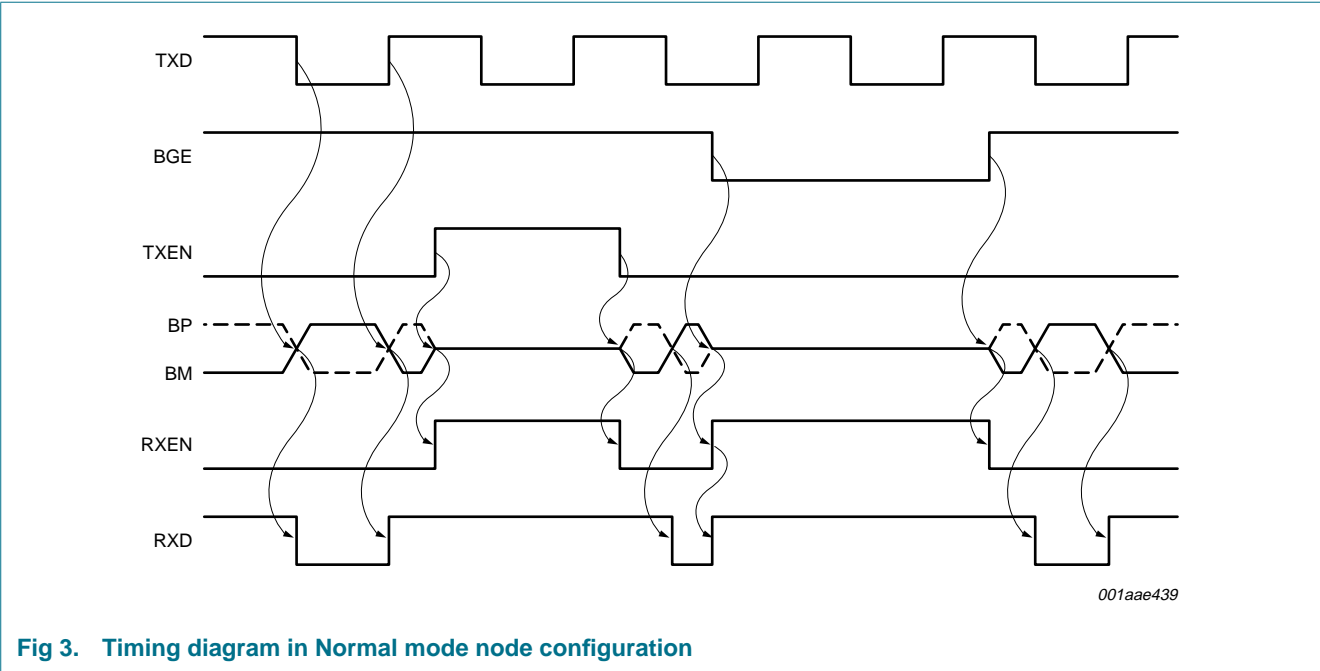
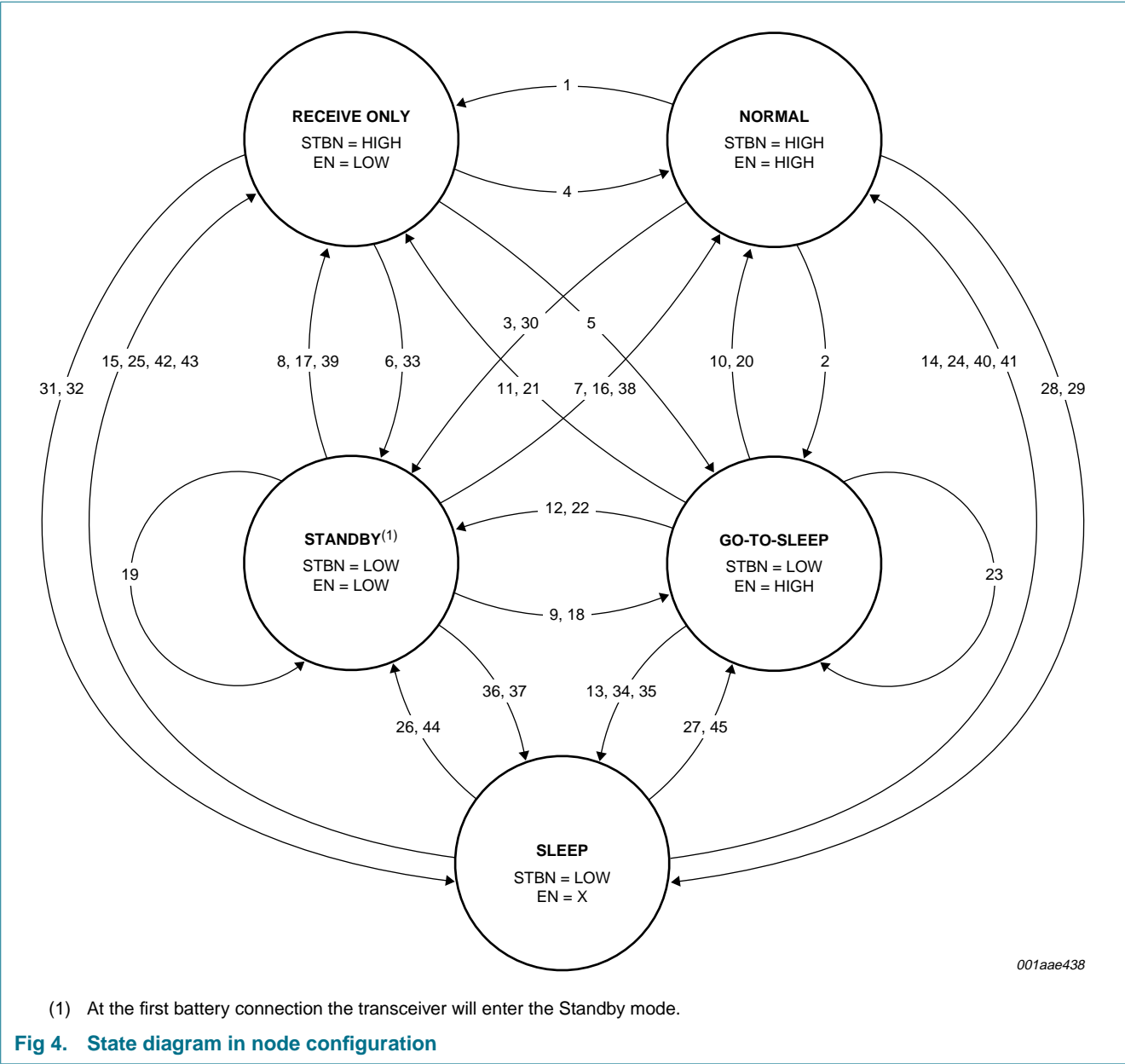


Fig 3. Timing diagram in Normal mode node configuration

The state diagram in node configuration is illustrated in [Figure 4](#).



The state transitions are represented with numbers, which correspond with the numbers in the last column of [Table 5](#) to [Table 8](#).

Table 5. State transitions forced by EN and STBN (node configuration)

→ indicates the action that initiates a transaction; →1 and →2 are the consequences of a transaction.

Transition from mode	Direction to mode	Transition number	Pin		Flag					Note
			STBN	EN	UV _{VIO}	UV _{VBAT}	UV _{VCC}	PWON	Wake	
Normal	Receive-only	1	H	→ L	cleared	cleared	cleared	cleared	cleared	
	Go-to-sleep	2	→ L	H	cleared	cleared	cleared	cleared	cleared	
	Standby	3	→ L	→ L	cleared	cleared	cleared	cleared	cleared	[1]
Receive-only	Normal	4	H	→ H	cleared	cleared	cleared	X	X	
	Go-to-sleep	5	→ L	→ H	cleared	cleared	cleared	X	X	
	Standby	6	→ L	L	cleared	cleared	cleared	X	X	
Standby	Normal	7	→ H	→ H	cleared	cleared	2 → cleared	X	1 → cleared	[2][3]
	Receive-only	8	→ H	L	cleared	cleared	2 → cleared	X	1 → set	[2][3]
	Go-to-sleep	9	L	→ H	cleared	cleared	X	X	X	
Go-to-sleep	Normal	10	→ H	H	cleared	cleared	cleared	X	1 → cleared	[2][4]
	Receive-only	11	→ H	→ L	cleared	cleared	cleared	X	1 → set	[2][4]
	Standby	12	L	→ L	cleared	cleared	X	X	X	[4]
	Sleep	13	L	H	cleared	cleared	X	X	cleared	[5]
Sleep	Normal	14	→ H	H	2 → cleared	2 → cleared	2 → cleared	X	1 → cleared	[2][3]
	Receive-only	15	→ H	L	2 → cleared	2 → cleared	2 → cleared	X	1 → set	[2][3]

[1] STBN must be set to LOW 60 μs after EN.

[2] Positive edge on pin STBN sets the wake flag. In the case of a transition to Normal mode the wake flag is immediately cleared.

[3] Setting the wake flag clears the UV_{VIO}, UV_{VBAT} and UV_{VCC} flag.

[4] Hold time of go-to-sleep is less than the minimum hold time.

[5] Hold time of go-to-sleep becomes greater than the minimum hold time.

Table 6. State transitions forced by a wake-up (node configuration)

→ indicates the action that initiates a transaction; →1 and →2 are the consequences of a transaction.

Transition from mode	Direction to mode	Transition number	Pin		Flag					Note
			STBN	EN	Wake	UV _{VIO}	UV _{VBAT}	UV _{VCC}	PWON	
Standby	Normal	16	H	H	→ set	cleared	cleared	1 → cleared	X	[1]
	Receive-only	17	H	L	→ set	cleared	cleared	1 → cleared	X	[1]
	Go-to-sleep	18	L	H	→ set	cleared	cleared	1 → cleared	X	[1]
	Standby	19	L	L	→ set	cleared	cleared	1 → cleared	X	[1]
Go-to-sleep	Normal	20	H	H	→ set	cleared	cleared	1 → cleared	X	[1]
	Receive-only	21	H	L	→ set	cleared	cleared	1 → cleared	X	[1]
	Standby	22	L	L	→ set	cleared	cleared	1 → cleared	X	[1]
	Go-to-sleep	23	L	H	→ set	cleared	cleared	1 → cleared	X	[1]
Sleep	Normal	24	H	H	→ set	1 → cleared	1 → cleared	1 → cleared	X	[1][2]
	Receive-only	25	H	L	→ set	1 → cleared	1 → cleared	1 → cleared	X	[1][2]
	Standby	26	L	L	→ set	1 → cleared	1 → cleared	1 → cleared	X	[1]
	Go-to-sleep	27	L	H	→ set	1 → cleared	1 → cleared	1 → cleared	X	[1][2]

[1] Setting the wake flag clears the UV_{VIO}, UV_{VBAT} and UV_{VCC} flag.

[2] Transition via Standby mode.

Table 7. State transitions forced by an undervoltage condition (node configuration)

→ indicates the action that initiates a transaction; →1 and →2 are the consequences of a transaction.

Transition from mode	Direction to mode	Transition number	Flag					Note
			UV _{VIO}	UV _{VBAT}	UV _{VCC}	PWON	Wake	
Normal	Sleep	28	→ set	cleared	cleared	cleared	cleared	[1]
	Sleep	29	cleared	→ set	cleared	cleared	cleared	[1]
	Standby	30	cleared	cleared	→ set	cleared	cleared	[1]
Receive-only	Sleep	31	→ set	cleared	cleared	X	1 → cleared	[1]
	Sleep	32	cleared	→ set	cleared	X	1 → cleared	[1]
	Standby	33	cleared	cleared	→ set	X	1 → cleared	[1]
Go-to-sleep	Sleep	34	→ set	cleared	cleared	X	1 → cleared	[1]
	Sleep	35	cleared	→ set	cleared	X	1 → cleared	[1]
Standby	Sleep	36	→ set	cleared	X	X	1 → cleared	[1][2]
	Sleep	37	cleared	→ set	X	X	1 → cleared	[1][3]

[1] UV_{VIO}, UV_{VBAT} or UV_{VCC} detected clears the wake flag.

[2] UV_{VIO} overrules UV_{VCC}.

[3] UV_{VBAT} overrules UV_{VCC}.

Table 8. State transitions forced by an undervoltage recovery (node configuration)

→ indicates the action that initiates a transaction; →1 and →2 are the consequences of a transaction.

Transition from mode	Direction to mode	Transition number	Pin		Flag					Note
			STBN	EN	UV _{VIO}	UV _{VBAT}	UV _{VCC}	PWON	Wake	
Standby	Normal	38	H	H	cleared	cleared	→ cleared	X	X	[1]
	Receive-only	39	H	L	cleared	cleared	→ cleared	X	X	[1]
Sleep	Normal	40	H	H	cleared	→ cleared	cleared	X	1 → cleared	[2][3]
	Normal	41	H	H	→ cleared	cleared	cleared	X	X	[4]
	Receive-only	42	H	L	cleared	→ cleared	cleared	X	1 → set	[2][3]
	Receive-only	43	H	L	→ cleared	cleared	cleared	X	X	[4]
	Standby	44	L	L	cleared	→ cleared	cleared	X	1 → set	[2][3]
	Sleep	45	L	X	→ cleared	cleared	cleared	X	cleared	[4]
	Go-to-sleep	46	L	H	cleared	→ cleared	cleared	X	1 → set	[2][3]
	Sleep	47	L	X	→ cleared	cleared	cleared	X	cleared	[4]

[1] Recovery of UV_{VCC} flag.

[2] Recovery of UV_{VBAT} flag.

[3] Clearing the UV_{VBAT} flag sets the wake flag. In the case of a transition to Normal mode the wake flag is immediately cleared.

[4] Recovery of UV_{VIO} flag.

7.2.1 Normal mode

In Normal mode the transceiver is able to transmit and receive data via the bus lines BP and BM. The output of the normal receiver is directly connected to pin RXD.

The transmitter behavior in Normal mode of operation, with no time-out present on pins TXEN and BGE and the temperature flag not set is given in [Table 9](#).

In this mode pins INH1 and INH2 are set HIGH.

Table 9. Transmitter function table

BGE	TXEN	TXD	Transmitter
L	X	X	transmitter is disabled
X	H	X	transmitter is disabled
H	L	H	transmitter is enabled; the bus lines are actively driven; BP is driven HIGH and BM is driven LOW
H	L	L	transmitter is enabled; the bus lines are actively driven; BP is driven LOW and BM is driven HIGH

7.2.2 Receive-only mode

In Receive-only mode the transceiver can only receive data. The transmitter is disabled, regardless of the voltages on pins BGE and TXEN.

In this mode pins INH1 and INH2 are set HIGH.

7.2.3 Standby mode

In Standby mode the transceiver has entered a low power mode which means very low current consumption. In the Standby mode the device is not able to transmit or receive data and the low power receiver is activated to monitor for bus wake-up patterns.

Standby mode can be entered if the correct polarity is applied to pins EN and STBN (see [Figure 4](#) and [Table 5](#)) or an undervoltage is present on pin V_{CC}; see [Figure 4](#).

In this mode the transceiver can be switched to any other mode if no undervoltage is present on pins V_{IO} and V_{BAT}.

Pin INH1 is set to HIGH. If the wake flag is set, pin INH2 is set to HIGH and pins RXEN and RXD are set to LOW, otherwise pin INH2 is floating and pins RXEN and RXD are set to HIGH; see [Section 7.5](#).

7.2.4 Go-to-sleep mode

In this mode the transceiver behaves as in Standby mode. If this mode is selected for a longer time than the go-to-sleep hold time parameter (minimum hold time) and the wake flag has been previously cleared, the transceiver will enter Sleep mode, regardless of the voltage on pin EN.

7.2.5 Sleep mode

In Sleep mode the transceiver has entered a low power mode. The only difference with Standby mode is that pin INH1 is also set floating. Sleep mode is also entered if the $UV_{V_{IO}}$ or $UV_{V_{BAT}}$ flag is set.

In this mode the transceiver can be switched to any other mode if no undervoltage is present on pins V_{IO} , V_{CC} and V_{BAT} . In case of an undervoltage on pin V_{CC} or V_{BAT} while V_{IO} is present, the wake flag is set by a positive edge on pin STBN.

The undervoltage flags will be reset by setting the wake flag, and therefore the transceiver will enter the mode indicated on pins EN and STBN if V_{IO} is present.

A detailed description of the wake-up mechanism is given in [Section 7.5](#).

7.3 Operating modes in star configuration

In star configuration mode control via pins EN and STBN is not possible. The transceiver autonomously controls the operating modes except in the case of wake-up.

The timing diagram of a transceiver configured in star configuration is illustrated in [Figure 6](#). The state diagram in star configuration is illustrated in [Figure 5](#). A detailed description of the pin signalling in star configuration is given in [Table 10](#).

If V_{IO} and (V_{BUF} or V_{BAT}) are within their operating range, pin ERRN will indicate the error flag.

Table 10. Pin signalling in star configuration

Mode	TRXD0 / TRXD1	ERRN ^[1]		RXEN		RXD		Transmitter	INH1	INH2
		LOW	HIGH	LOW	HIGH	LOW	HIGH			
Star-transmit	output ^[2] input ^[3]	error flag set	error flag reset	bus activity	bus idle	bus DATA_0	bus DATA_1 or idle	enabled	HIGH	HIGH
Star-receive	output							disabled		
Star-idle	input									
Star-locked	input									
Star-standby	input	error flag set ^[4]	error flag reset	wake flag set ^[4]	wake flag reset	wake flag set ^[5]	wake flag reset			
Star-sleep	input								float	float

[1] Pin ERRN provides a serial interface for retrieving diagnostic information.

[2] TRXD lines switched as output if TXEN activity is the initiator for Star-transmit mode.

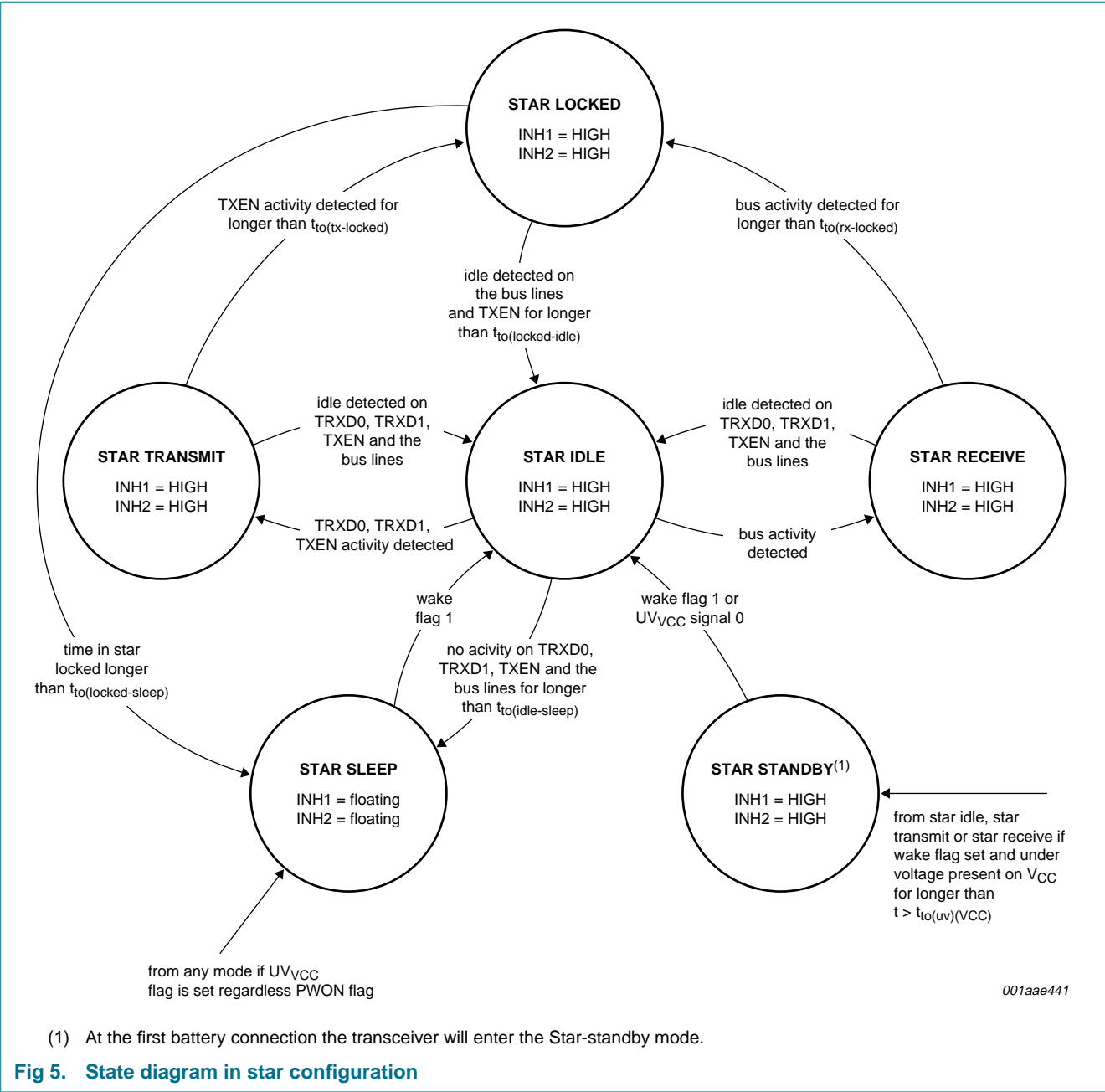
[3] TRXD lines are switched as input if TRXD activity is the initiator for Star-transmit mode.

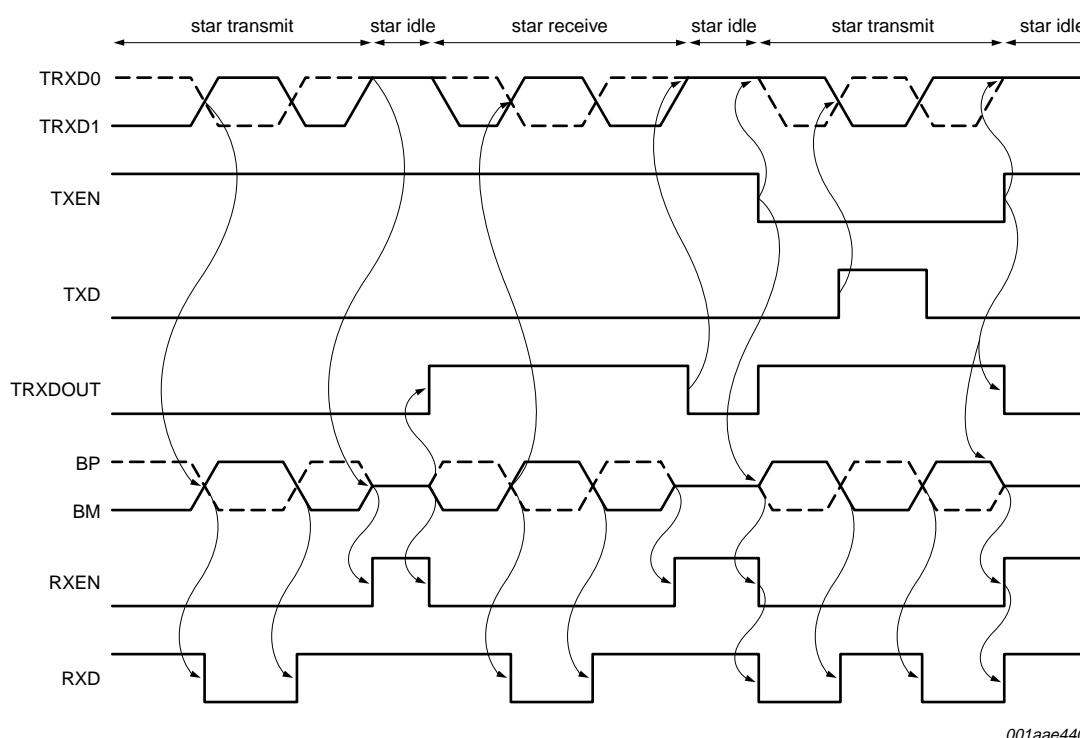
[4] Valid if V_{IO} and (V_{BUF} or V_{BAT}) are present.

[5] Valid if V_{IO} and V_{BUF} are present.

Pin BGE must be HIGH in order to enable the transmitter via pin TXEN. If pin BGE is LOW, it is not possible to activate the transmitter via pin TXEN. If pin TXEN is not used (no controller connected to the transceiver), it has to be connected to pin GND in order to prevent TXEN activity detection.

In all normal modes pin RXD is connected to the output of the normal mode receiver and therefore represents the data on the bus lines.





TRXDOUT is a virtual signal that indicates the state of the TRXD lines. TRXDOUT HIGH means TRXD lines switched as output. TRXDOUT LOW means TRXD lines switched as input.

Fig 6. Timing diagram in star configuration

7.3.1 Star-idle mode

This mode is entered if one of the following events occurs:

- From Star-receive mode and Star-transmit mode if idle is detected on the bus lines, on pin TXEN and on pins TRXD0 and TRXD1.
- If the transceiver is in Star-locked mode and idle is detected on the bus lines and pin TXEN for longer than $t_{to(locked-idle)}$.
- If the transceiver is in Star-standby mode and the wake flag is set or no undervoltage is present.
- If the transceiver is in Star-sleep mode and the wake flag is set, the transceiver enters Star-idle mode in order to obtain a stable starting point (no glitches on the bus lines etc.).

In Star-idle mode the transceiver monitors pins TXEN, TRXD0 and TRXD1 and the bus lines for activity. In this mode the transmitter is disabled.

7.3.2 Star-transmit mode

This mode is entered if one of the following events occur:

- If the transceiver is in Star-idle mode and activity is detected on pin TXEN.
- If the transceiver is in Star-idle mode and activity is detected on pins TRXD0 and TRXD1.

In Star-transmit mode the transmitter is enabled and the transceiver can transmit data on the bus lines and on the TRXD lines. It transmits the data received on pins TXD or TRXD0 and TRXD1, depending on where activity is detected:

- If activity is detected on the TRXD lines, the transceiver transmits data from pins TRXD0 and TRXD1 to the bus.
- If activity is detected on the TXEN, the transceiver transmits data from pin TXD to the bus and to the TRXD lines.

7.3.3 Star-receive mode

This mode is entered if the transceiver is in Star-idle mode and activity has been detected on the bus lines.

In Star-receive mode the transceiver transmits data received on the bus via the TRXD0 and TRXD1 lines to other transceivers connected to the TRXD lines. The transmitter is always disabled. RXD, which represents the data on the bus lines, is output at TRXD0 and TRXD1.

7.3.4 Star-standby mode

This mode is entered if one of the following events occur:

- From Star-idle, Star-transmit or Star-receive modes if the wake flag is set and an undervoltage on pin V_{CC} is present for longer than $t_{lo(uv)}(V_{CC})$.
- If the PWON flag is set.

In Star-standby mode the transceiver has entered a low power mode. In this mode the current consumption is as low as possible to prevent discharging the capacitor at pin V_{BUF} .

If pins V_{IO} and V_{BUF} are within their operating range, pins RXD and RXEN will indicate the wake flag.

7.3.5 Star-sleep mode

This mode is entered if one of the following events occur:

- From any mode if an undervoltage on pin V_{CC} is present for longer than $t_{det(uv)}(V_{CC})$.
- If the transceiver is in Star-idle mode and no activity is detected on the bus lines and pins TXEN, TRXD0 and TRXD1 for longer than $t_{to(idle-sleep)}$.
- If Star-locked mode is active for longer than $t_{to(locked-sleep)}$.

In Star-sleep mode the transceiver has entered a low power mode. In this mode the current consumption is as low as possible to prevent the car battery from discharging. The inhibit switches are switched off.

In this mode the wake flag wakes the transceiver. A detailed description of the wake-up mechanism is given in [Section 7.5](#).

If pins V_{IO} and V_{BUF} are within their operating range, pins RXD and RXEN will indicate the wake flag.

7.3.6 Star-locked mode

This mode is entered if one of the following events occur:

- If the transceiver is in Star-transmit mode and activity on pin TXEN is detected for longer than $t_{to(tx-locked)}$.
- If the transceiver is in Star-receive mode and activity is detected on the bus lines for longer than $t_{to(rx-locked)}$.

This mode is a fail-silent mode and in this mode the transmitter is disabled.

7.4 Start-up

At power-up V_{BAT} should be supplied first. When V_{BAT} reaches 6.5 V, V_{CC} and V_{IO} may be switched on with a delay of at least 60 μ s with respect to V_{BAT} .

7.4.1 Node configuration

Node configuration can be selected by applying a voltage lower than $0.3V_{BUF}$ to pins TRXD0 and TRXD1 during power-on. Node configuration is latched by resetting the PWON flag while the voltage on pins TRXD0 and TRXD1 is lower than $0.3V_{BUF}$; see [Section 7.7.4](#) for (re)setting the PWON flag.

7.4.2 Star configuration

Star configuration can be selected by applying a voltage higher than $0.7V_{BUF}$ to pins TRXD0 or TRXD1 during power-on. Star configuration is latched by resetting the PWON flag while one of the voltages on pins TRXD0 or TRXD1 is higher than $0.7V_{BUF}$. See [Section 7.7.4](#) for (re)setting the PWON flag. In this case the transceiver goes from Star-standby mode to Star-idle mode.

7.5 Wake-up mechanism

7.5.1 Node configuration

In Sleep mode (pins INH1 and INH2 are switched off), the transceiver will enter Standby mode or Go-to-sleep mode (depending on the value at pin EN), if the wake flag is set. Consequently, pins INH1 and INH2 are switched on.

If no undervoltage is present on pins V_{IO} and V_{BAT} , the transceiver switches immediately to the mode indicated on pins EN and STBN.

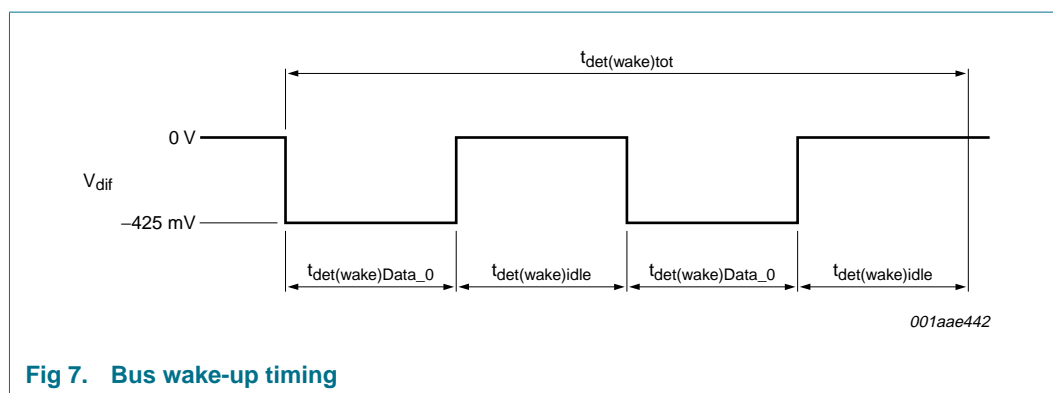
In Standby, Go-to-sleep and Sleep mode pins RXD and RXEN are driven LOW if the wake flag is set.

7.5.2 Star configuration

In Star-sleep mode (pins INH1 and INH2 are switched off), the transceiver will enter Star-idle mode (pins INH1 and INH2 are switched on) if the wake flag is set. After entering Star-idle mode the transceiver monitors for activity to choose the appropriate mode transition (see [Figure 5](#)).

7.5.3 Bus wake-up

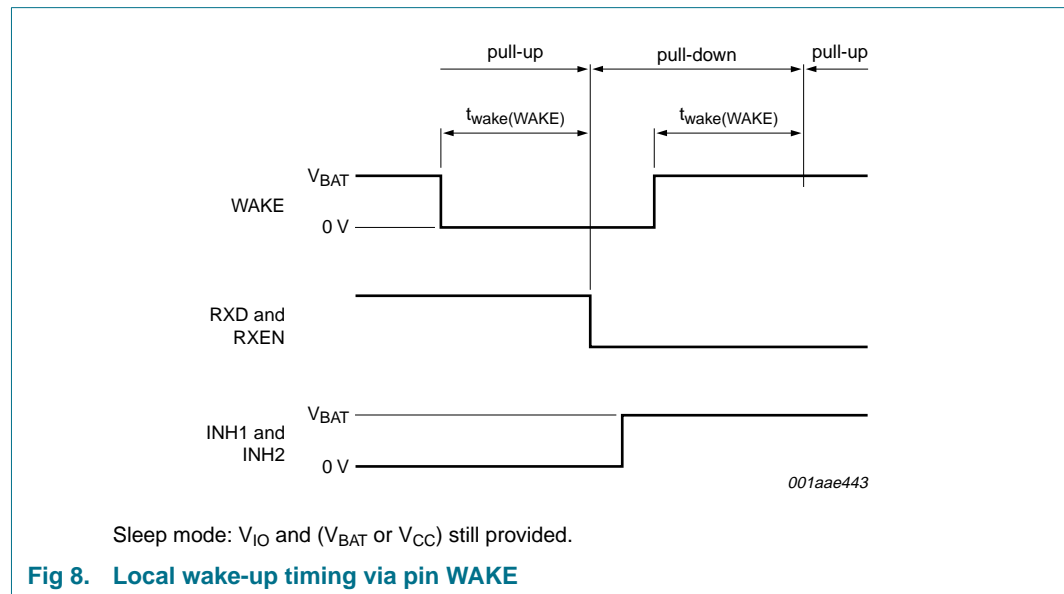
Bus wake-up is detected if two consecutive DATA_0 of at least $t_{\text{det(wake)DATA_0}}$ separated by an idle or DATA_1 of at least $t_{\text{det(wake)idle}}$, followed by an idle or DATA_1 of at least $t_{\text{det(wake)idle}}$ are present on the bus lines within $t_{\text{det(wake)tot}}$.



7.5.4 Local wake-up via pin WAKE

If the voltage on pin WAKE is lower than $V_{th(det)(WAKE)}$ for longer than $t_{wake(WAKE)}$ (falling edge on pin WAKE) a local wake-up event on pin WAKE is detected. At the same time, the biasing of this pin is switched to pull-down.

If the voltage on pin WAKE is higher than $V_{th(det)(WAKE)}$ for longer than $t_{wake(WAKE)}$, the biasing of this pin is switched to pull-up, and no local wake-up will be detected.



7.6 Fail silent behavior

In order to be fail silent, undervoltage detection and a reset mechanism for the digital state machine is implemented.

If an undervoltage is detected on pins V_{CC} , V_{IO} and/or V_{BAT} , the transceiver will enter a low power mode. This ensures a passive and defined behavior of the transmitter and receiver in case of an undervoltage detection.

In the region between the minimum operating voltage and the undervoltage detection threshold, the principle function of the transmitter and receiver is maintained. However, in this region parameters (e.g. thresholds and delays of the transmitter and receiver) may deviate from the range specified for the operating range.

The digital state machine is supplied out of V_{CC} , V_{IO} or V_{BAT} , dependent on which voltage is available. Therefore, the digital state machine remains properly supplied as long as one supply voltage (V_{CC} , V_{IO} or V_{BAT}) is available.

If the voltage on all pins V_{CC} , V_{IO} and V_{BAT} breaks down, a reset signal will be given to the digital state machine as soon as the internal supply voltage for the digital state machine is not sufficient for proper operation of the state machine. This ensures a passive and defined behavior of the digital state machine in case of an overall supply voltage breakdown.

7.6.1 V_{BAT} undervoltage

- Node configuration: If the $UV_{V_{BAT}}$ flag is set the transceiver will enter Sleep mode (pins INH1 and INH2 are switched off) regardless of the voltage present on pins EN and STBN. If the undervoltage recovers the wake flag will be set and the transceiver will enter the mode determined by the voltages on pins EN and STBN.
- Star configuration: The TJA1080 in star configuration is able to transmit and receive data as long as V_{CC} and V_{IO} are within their operating range, regardless of the undervoltage on V_{BAT} .

7.6.2 V_{CC} undervoltage

- Node configuration: If the $UV_{V_{CC}}$ flag is set the transceiver will enter the Standby mode (pin INH2 is switched off) regardless of the voltage present on pins EN and STBN. If the undervoltage recovers or the wake flag is set mode switching via pins EN and STBN is possible.
- Star configuration: If the $UV_{V_{CC}}$ flag is set the transceiver will enter the Star-sleep mode.

7.6.3 V_{IO} undervoltage

- Node configuration: If the voltage on pin V_{IO} is lower than $V_{uvd(V_{IO})}$ (even if the $UV_{V_{IO}}$ flag is reset) pins EN, STBN, TXD and BGE are set LOW (internally) and pin TXEN is set HIGH (internally). If the $UV_{V_{IO}}$ flag is set the transceiver will enter Sleep mode (pins INH1 and INH2 are switched off). If the undervoltage recovers or the wake flag is set, mode switching via pins EN and STBN is possible.
- Star configuration: If an undervoltage is present on pin V_{IO} (even if the $UV_{V_{IO}}$ flag is reset) pins EN, STBN, TXD and BGE are set LOW (internally) and pin TXEN is set HIGH (internally). If the V_{IO} undervoltage flag is set, pin INH1 is switched off. If an undervoltage is present on pin V_{IO} and V_{CC} is within the operating range, the TJA1080 will forward the received data on TRXD or bus lines to all other branches.

7.7 Flags

7.7.1 Local wake-up source flag

The local wake-up source flag can only be set in a low power mode. When a wake-up event on pin WAKE is detected (see [Section 7.5.4](#)) it sets the local wake-up source flag. The local wake-up source flag is reset by entering a low power mode.

7.7.2 Remote wake-up source flag

The remote wake-up source flag can only be set in a low power mode. When a bus wake-up event is detected on the bus lines (see [Section 7.5.3](#)) it sets the remote wake-up source flag. The remote wake-up source flag is reset by entering a low power mode.

7.7.3 Wake flag

The wake flag is set if one of the following events occurs:

- The local or remote wake-up source flag is set (edge sensitive)
- A positive edge is detected on pin STBN if V_{IO} is present
- Recovery of the UV_{VBAT} flag (only in node configuration)
- By recognizing activity on pins TRXD0 and TRXD1 (only in star configuration)

In node configuration the wake flag is reset by entering Normal mode, a low power mode or setting one of the undervoltage flags. In star configuration the wake flag is reset by entering a low power mode or by recovery of the UV_{VCC} signal (without $t_{rec(uv)(VCC)}$).

7.7.4 Power-on flag

The PWON flag is set if the internal supply voltage for the digital part becomes higher than the lowest value it needs to operate. In node configuration, entering Normal mode resets the PWON flag. In star configuration the PWON flag is reset when the UV_{VCC} signal goes LOW (no undervoltage detected).

7.7.5 Node configuration flag

Configuration flag set means node configuration.

7.7.6 Temperature medium flag

The temperature medium flag is set if the junction temperature exceeds $T_{j(warn)(medium)}$ in a normal power mode. The temperature medium flag is reset when the junction temperature becomes lower than $T_{j(warn)(medium)}$ in a normal power mode and after a read of the status register in a low power mode. No action will be taken if this flag is set.

7.7.7 Temperature high flag

The temperature high flag is set if the junction temperature exceeds $T_{j(dis)(high)}$ in a normal power mode.

In node configuration the temperature high flag is reset if a negative edge is applied to pin TXEN while the junction temperature is lower than $T_{j(dis)(high)}$ in a normal power mode. In star configuration the temperature high flag is reset by any activity detection (edge) while the junction temperature is lower than $T_{j(dis)(high)}$ in a normal power mode.

If the temperature high flag is set the transmitter is disabled and pins TRXD0 and TRXD1 are switched off.

7.7.8 TXEN_BGE clamped flag

The TXEN_BGE clamped flag is set if pin TXEN is LOW and pin BGE is HIGH for longer than $t_{detCL(TXEN_BGE)}$. The TXEN_BGE clamped flag is reset if pin TXEN is HIGH or pin BGE is LOW. If the TXEN_BGE flag is set, the transmitter is disabled.

7.7.9 Bus error flag

The bus error flag is set if pin TXEN is LOW and pin BGE is HIGH and the data received from the bus lines (pins BP and BM) is different to that received on pin TXD. Additionally in star configuration the bus error flag is also set if the data received on the bus lines is different to that received on pins TRXD0 and TRXD1. The TJA1080 also expects that a data frame begins with a bit value other than the last bit of the previous data frame.

This is the case for a valid data frame which begins with the DATA_0 period of the Transmission Start Sequence (TSS) and ends with the DATA_1 bit of the Frame End Sequence (FES). Any violation of this frame format will be detected by the TJA1080. Consequently, when transmitting a wake-up pattern, a bus error will be signalled. This error indication should be ignored and the status register should be cleared by reading the vector.

No action will be taken if the bus error flag is set.

7.7.10 UV_{V_{BAT}} flag

The UV_{V_{BAT}} flag is set if the voltage on pin V_{BAT} is lower than V_{uvd(V_{BAT})}. The UV_{V_{BAT}} flag is reset if the voltage is higher than V_{uvd(V_{BAT})} or by setting the wake flag; see [Section 7.6.1](#).

7.7.11 UV_{V_{CC}} flag

The UV_{V_{CC}} flag is set if the voltage on pin V_{CC} is lower than V_{uvd(V_{CC})} for longer than t_{det(uv)}(V_{CC}). The flag is reset if the voltage on pin V_{CC} is higher than V_{uvd(V_{CC})} for longer than t_{rec(uv)}(V_{CC}) or the wake flag is set; see [Section 7.6.2](#).

7.7.12 UV_{V_{IO}} flag

The UV_{V_{IO}} flag is set if the voltage on pin V_{IO} is lower than V_{uvd(V_{IO})} for longer than t_{det(uv)}(V_{IO}). The flag is reset if the voltage on pin V_{IO} is higher than V_{uvd(V_{IO})} or the wake flag is set; see [Section 7.6.3](#).

7.7.13 Error flag

The error flag is set if one of the status bits S4 to S12 is set. The error flag is reset if none of the S4 to S12 status bits are set; see [Table 11](#).

7.8 TRXD collision

A TRXD collision is detected when both TRXD lines are LOW in star configuration.

7.9 Status register

The status register can be read out on pin ERRN by using pin EN as clock; the status bits are given in [Table 11](#). The timing diagram is illustrated in [Figure 9](#).

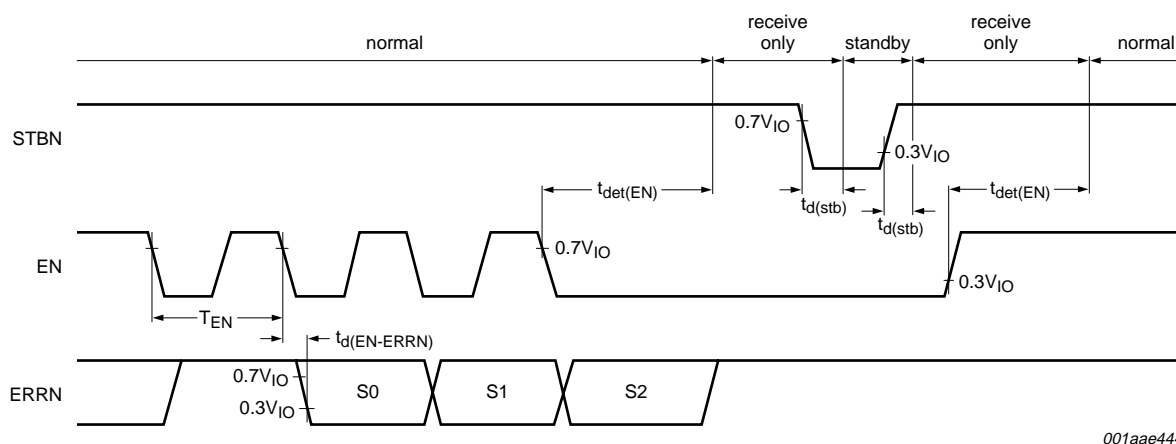
The status register is accessible if:

- UV_{V_{IO}} flag is not set and the voltage on pin V_{IO} is between 4.75 V and 5.25 V
- UV_{V_{CC}} flag is not set and the voltage on pin V_{IO} is between 2.2 V and 4.75 V

Pin ERRN is LOW if the corresponding status bit is set.

Table 11. Status bits

Bit number	Status bit	Description
S0	LOCAL WAKEUP	local wake-up source flag is redirected to this bit
S1	REMOTE WAKEUP	remote wake-up source flag is redirected to this bit
S2	NODE CONFIG	node configuration flag is redirected to this bit
S3	PWON	status bit set means PWON flag has been set previously
S4	BUS ERROR	status bit set means bus error flag has been set previously
S5	TEMP HIGH	status bit set means temperature high flag has been set previously
S6	TEMP MEDIUM	status bit set means temperature medium flag has been set previously
S7	TXEN_BGE CLAMPED	status bit set means TXEN_BGE clamped flag has been set previously
S8	UVVBAT	status bit set means UV_{VBAT} flag has been set previously
S9	UVVCC	status bit set means UV_{VCC} flag has been set previously
S10	UVVIO	status bit set means UV_{VIO} flag has been set previously
S11	STAR LOCKED	status bit is set if Star-locked mode has been entered previously
S12	TRXD COLLISION	status bit is set if a TRXD collision has been detected previously



001aae444

Fig 9. Timing diagram for status bits

8. Limiting values

Table 12. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). All voltages are referenced to GND.

Symbol	Parameter	Conditions	Min	Max	Unit
V _{BAT}	supply voltage on pin V _{BAT}	no time limit	-0.3	+60	V
		operating range	6.5	60	V
V _{CC}	supply voltage	no time limit	-0.3	+5.5	V
		operating range	4.75	5.25	V
V _{BUF}	supply voltage on pin V _{BUF}	no time limit	-0.3	+5.5	V
		operating range	4.75	5.25	V
V _{IO}	supply voltage on pin V _{IO}	no time limit	-0.3	+5.5	V
		operating range	2.2	5.25	V
V _{INH1}	voltage on pin INH1		-0.3	V _{BAT} + 0.3	V
V _{INH2}	voltage on pin INH2		-0.3	V _{BAT} + 0.3	V
V _{WAKE}	voltage on pin WAKE		-0.3	V _{BAT} + 0.3	V
I _{O(WAKE)}	output current on pin WAKE	pin GND not connected	-15	-	mA
V _{BGE}	voltage on pin BGE	no time limit	-0.3	V _{IO} + 0.3	V
V _{TXEN}	voltage on pin TXEN	no time limit	-0.3	V _{IO} + 0.3	V
V _{TXD}	voltage on pin TXD	no time limit	-0.3	V _{IO} + 0.3	V
V _{ERRN}	voltage on pin ERRN	no time limit	-0.3	V _{IO} + 0.3	V
V _{RXD}	voltage on pin RXD	no time limit	-0.3	V _{IO} + 0.3	V
V _{RXEN}	voltage on pin RXEN	no time limit	-0.3	V _{IO} + 0.3	V
V _{EN}	voltage on pin EN	no time limit	-0.3	+5.5	V
V _{STBN}	voltage on pin STBN	no time limit	-0.3	+5.5	V
V _{TRXD0}	voltage on pin TRXD0	no time limit	-0.3	+5.5	V
V _{TRXD1}	voltage on pin TRXD1	no time limit	-0.3	+5.5	V
V _{BP}	voltage on pin BP	no time limit	-60	+60	V
V _{BM}	voltage on pin BM	no time limit	-60	+60	V
V _{trt}	transient voltage	on pins BP and BM	[1] -200	+200	V
		on pin V _{BAT}	[2] -200	+200	V
		on pin V _{BAT}	[3] 6.5	60	V
		on pin V _{BAT}	[4] -	60	V
T _{stg}	storage temperature		-55	+150	°C
T _{vj}	virtual junction temperature		[5] -40	+150	°C
V _{ESD}	electrostatic discharge voltage	HBM on pins BP and BM to ground	[6] -8.0	+8.0	kV
		HBM at any other pin	[7] -4.0	+4.0	kV
		MM on all pins	[8] -200	+200	V
		CDM on all pins	[9] -1000	+1000	V

[1] According to ISO 7637, part 3 test pulses a and b; Class C; see [Figure 13](#); R_L = 45 Ω; C_L = 100 pF.

[2] According to ISO 7637, part 2 test pulses 1, 2, 3a and 3b; Class C; see [Figure 13](#); R_L = 45 Ω; C_L = 100 pF.

[3] According to ISO 7637, part 2 test pulse 4; Class C; see [Figure 13](#); R_L = 45 Ω; C_L = 100 pF.

[4] According to ISO 7637, part 2 test pulse 5b; Class C; see [Figure 13](#); R_L = 45 Ω; C_L = 100 pF; V_{BAT} = 24 V.

- [5] In accordance with IEC 60747-1. An alternative definition of virtual junction temperature T_{vj} is: $T_{vj} = T_{amb} + TD \times R_{th(j-a)}$, where $R_{th(j-a)}$ is a fixed value to be used for the calculation of T_{vj} . The rating for T_{vj} limits the allowable combinations of power dissipation (P) and ambient temperature (T_{amb}).
- [6] HBM: C = 100 pF; R = 1.5 kΩ.
- [7] HBM: C = 100 pF; R = 1.5 kΩ.
- [8] MM: C = 200 pF; L = 0.75 μH; R = 10 Ω.
- [9] CDM: C = 330 pF; R = 150 Ω.

9. Thermal characteristics

Table 13. Thermal characteristics

Symbol	Parameter	Conditions	Typ	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	126	K/W
$R_{th(j-s)}$	thermal resistance from junction to substrate	in free air	-	K/W

10. Static characteristics

Table 14. Static characteristics

All parameters are guaranteed for $V_{BAT} = 6.5\text{ V to }60\text{ V}$; $V_{CC} = 4.75\text{ V to }5.25\text{ V}$; $V_{BUF} = 4.75\text{ V to }5.25\text{ V}$; $V_{IO} = 2.2\text{ V to }5.25\text{ V}$; $T_{vj} = -40\text{ °C to }+150\text{ °C}$; $R_{bus} = 45\text{ Ω}$; $R_{TRXD} = 200\text{ Ω}$ unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.^{[1][2]}

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Pin V_{BAT}						
I_{BAT}	supply current on pin V_{BAT}	low power modes in node configuration	-	-	50	μA
		Star-sleep mode	-	-	50	μA
		Star-standby mode	-	-	150	μA
		normal power modes	-	-	1	mA
$V_{uvd(VBAT)}$	undervoltage detection voltage on pin V_{BAT}		2.75	-	4.5	V
Pin V_{CC}						
I_{CC}	supply current	low power modes	-1	0	+5	μA
		Normal mode; $V_{BGE} = 0\text{ V}$; $V_{TXEN} = V_{IO}$; Receive-only mode; Star-idle mode	-	-	15	mA
		Normal mode; $V_{BGE} = V_{IO}$; $V_{TXEN} = 0\text{ V}$; V_{BUF} open	[3] -	-	35	mA
		Normal mode; $V_{BGE} = V_{IO}$; $V_{TXEN} = 0\text{ V}$; $R_{bus} = \infty\text{ Ω}$	-	-	15	mA
		Star-transmit mode	-	-	62	mA
		Star-receive mode	-	-	42	mA
$V_{uvd(VCC)}$	undervoltage detection voltage on pin V_{CC}		2.75	-	4.5	V
Pin V_{IO}						
I_{IO}	supply current on pin V_{IO}	low power modes	-1	+1	+5	μA
		Normal and Receive-only mode; $V_{TXD} = V_{IO}$	-	-	1000	μA

Table 14. Static characteristics ...continued

All parameters are guaranteed for $V_{BAT} = 6.5\text{ V to }60\text{ V}$; $V_{CC} = 4.75\text{ V to }5.25\text{ V}$; $V_{BUF} = 4.75\text{ V to }5.25\text{ V}$; $V_{IO} = 2.2\text{ V to }5.25\text{ V}$; $T_{vj} = -40\text{ }^{\circ}\text{C to }+150\text{ }^{\circ}\text{C}$; $R_{bus} = 45\text{ }\Omega$; $R_{TRXD} = 200\text{ }\Omega$ unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.^{[1][2]}

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{UVD}(V_{IO})$	undervoltage detection voltage on pin V_{IO}		1	-	2	V
$V_{UVR}(V_{IO})$	undervoltage recovery voltage on pin V_{IO}		1	-	2.2	V
$V_{UVHYS}(V_{IO})$	undervoltage hysteresis voltage on pin V_{IO}		25	-	200	mV
Pin V_{BUF}						
I_{BUF}	supply current on pin V_{BUF}	low power modes in node configuration	-1	0	+5	μA
		low power modes in star configuration				
		$V_{BUF} = 0\text{ V}$; $V_{CC} = 0\text{ V}$	-40	-20	+1	μA
		$V_{BUF} = 5.25\text{ V}$	-1	0	+10	μA
		Normal mode; $V_{BGE} = V_{IO}$; $V_{TXEN} = 0\text{ V}$; $V_{BUF} = V_{CC}$	[3] -	-	35	mA
		Star-transmit mode	-	-	62	mA
		Star-receive mode	-	-	42	mA
		Normal mode; $V_{BGE} = 0\text{ V}$; $V_{TXEN} = V_{IO}$; Receive-only mode; Star-idle mode	-	-	15	mA
$V_{BUF(on)}$	on-state voltage on pin V_{BUF}	V_{CC} switch is switched on; Normal mode; $V_{BGE} = V_{IO}$; $V_{TXEN} = 0\text{ V}$; $V_{CC} >$ maximum value of $V_{UVD}(V_{CC})$	$V_{CC} - 0.25$	-	V_{CC}	V
$V_{BUF(off)}$	off-state voltage on pin V_{BUF}	V_{CC} switch is switched off; low power modes in star configuration; $V_{CC} <$ minimum value of $V_{UVD}(V_{CC})$	4.5	-	5.25	V
Pin EN						
$V_{IH}(EN)$	HIGH-level input voltage on pin EN		$0.7V_{IO}$	-	5.5	V
$V_{IL}(EN)$	LOW-level input voltage on pin EN		-0.3	-	$0.3V_{IO}$	V
$I_{IH}(EN)$	HIGH-level input current on pin EN	$V_{EN} = 0.7V_{IO}$	3	-	11	μA
$I_{IL}(EN)$	LOW-level input current on pin EN	$V_{EN} = 0\text{ V}$	-1	0	+1	μA
Pin STBN						
$V_{IH}(STBN)$	HIGH-level input voltage on pin STBN		$0.7V_{IO}$	-	5.5	V
$V_{IL}(STBN)$	LOW-level input voltage on pin STBN		-0.3	-	$0.3V_{IO}$	V
$I_{IH}(STBN)$	HIGH-level input current on pin STBN	$V_{STBN} = 0.7V_{IO}$	3	-	11	μA

Table 14. Static characteristics ...continued

All parameters are guaranteed for $V_{BAT} = 6.5\text{ V to }60\text{ V}$; $V_{CC} = 4.75\text{ V to }5.25\text{ V}$; $V_{BUF} = 4.75\text{ V to }5.25\text{ V}$; $V_{IO} = 2.2\text{ V to }5.25\text{ V}$; $T_{vj} = -40\text{ }^{\circ}\text{C to }+150\text{ }^{\circ}\text{C}$; $R_{bus} = 45\text{ }\Omega$; $R_{TRXD} = 200\text{ }\Omega$ unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.^{[1][2]}

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$I_{IL(STBN)}$	LOW-level input current on pin STBN	$V_{STBN} = 0\text{ V}$	-1	0	+1	μA
Pin TXEN						
$V_{IH(TXEN)}$	HIGH-level input voltage on pin TXEN		$0.7V_{IO}$	-	$V_{IO} + 0.3$	V
$V_{IL(TXEN)}$	LOW-level input voltage on pin TXEN		-0.3	-	$0.3V_{IO}$	V
$I_{IH(TXEN)}$	HIGH-level input current on pin TXEN	$V_{TXEN} = V_{IO}$	-1	0	+1	μA
$I_{IL(TXEN)}$	LOW-level input current on pin TXEN	$V_{TXEN} = 0.3V_{IO}$	-12	-	-3	μA
$I_{L(TXEN)}$	leakage current on pin TXEN	$V_{TXEN} = 5.25\text{ V}$; $V_{IO} = 0\text{ V}$	-1	0	+1	μA
Pin BGE						
$V_{IH(BGE)}$	HIGH-level input voltage on pin BGE		$0.7V_{IO}$	-	$V_{IO} + 0.3$	V
$V_{IL(BGE)}$	LOW-level input voltage on pin BGE		-0.3	-	$0.3V_{IO}$	V
$I_{IH(BGE)}$	HIGH-level input current on pin BGE	$V_{BGE} = 0.7V_{IO}$	3	-	11	μA
$I_{IL(BGE)}$	LOW-level input current on pin BGE	$V_{BGE} = 0\text{ V}$	-1	0	+1	μA
Pin TXD						
$V_{IH(TXD)}$	HIGH-level input voltage on pin TXD	normal power modes	$0.7V_{IO}$	-	$V_{IO} + 0.3$	V
$V_{IL(TXD)}$	LOW-level input voltage on pin TXD	normal power modes	-0.3	-	$0.3V_{IO}$	V
$I_{IH(TXD)}$	HIGH-level input current on pin TXD	$V_{TXD} = V_{IO}$	70	300	650	μA
$I_{IL(TXD)}$	LOW-level input current on pin TXD	normal power modes; $V_{TXD} = 0\text{ V}$	-5	0	+5	μA
		low power modes	-1	0	+1	μA
$I_{LI(TXD)}$	input leakage current on pin TXD	$V_{TXD} = 5.25\text{ V}$; $V_{IO} = 0\text{ V}$	-1	0	+1	μA
Pin RXD						
$I_{OH(RXD)}$	HIGH-level output current on pin RXD	$V_{RXD} = V_{IO} - 0.4\text{ V}$; $V_{IO} = V_{CC}$	-20	-	-2	mA
$I_{OL(RXD)}$	LOW-level output current on pin RXD	$V_{RXD} = 0.4\text{ V}$	2	-	20	mA

Table 14. Static characteristics ...continued

All parameters are guaranteed for $V_{BAT} = 6.5\text{ V}$ to 60 V ; $V_{CC} = 4.75\text{ V}$ to 5.25 V ; $V_{BUF} = 4.75\text{ V}$ to 5.25 V ; $V_{IO} = 2.2\text{ V}$ to 5.25 V ; $T_{vj} = -40\text{ }^{\circ}\text{C}$ to $+150\text{ }^{\circ}\text{C}$; $R_{bus} = 45\text{ }\Omega$; $R_{TRXD} = 200\text{ }\Omega$ unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.^{[1][2]}

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Pin ERRN						
$I_{OH(ERRN)}$	HIGH-level output current on pin ERRN	node configuration; $V_{ERRN} = V_{IO} - 0.4\text{ V}$; $V_{IO} = V_{CC}$	-1500	-550	-100	μA
		star configuration; $V_{ERRN} = V_{IO} - 0.4\text{ V}$; $V_{IO} = V_{CC}$	-1	0	+1	μA
$I_{OL(ERRN)}$	LOW-level output current on pin ERRN	$V_{ERRN} = 0.4\text{ V}$	300	700	1500	μA
Pin RXEN						
$I_{OH(RXEN)}$	HIGH-level output current on pin RXEN	$V_{RXEN} = V_{IO} - 0.4\text{ V}$; $V_{IO} = V_{CC}$	-4	-1.5	-0.5	mA
$I_{OL(RXEN)}$	LOW-level output current on pin RXEN	$V_{RXEN} = 0.4\text{ V}$	1	3	8	mA
Pins TRXD0 and TRXD1						
$V_{IH(TRXD0)}$	HIGH-level input voltage on pin TRXD0	Star-idle and Star-transmit mode	$0.7V_{BUF}$	-	$V_{BUF} + 0.3$	V
$V_{IL(TRXD0)}$	LOW-level input voltage on pin TRXD0	Star-idle and Star-transmit mode	-0.3	-	$0.3V_{BUF}$	V
$V_{OL(TRXD0)}$	LOW-level output voltage on pin TRXD0	$R_{pu} = 200\text{ }\Omega$	-0.3	-	+0.8	V
$V_{IH(TRXD1)}$	HIGH-level input voltage on pin TRXD1	Star-idle and Star-transmit mode	$0.7V_{BUF}$	-	$V_{BUF} + 0.3$	V
$V_{IL(TRXD1)}$	LOW-level input voltage on pin TRXD1	Star-idle and Star-transmit mode	-0.3	-	$0.3V_{BUF}$	V
$V_{OL(TRXD1)}$	LOW-level output voltage on pin TRXD1	$R_{pu} = 200\text{ }\Omega$	-0.3	-	+0.8	V
Pins BP and BM						
$V_{o(idle)(BP)}$	idle output voltage on pin BP	Normal, Receive-only, Star-idle, Star-transmit and Star-receive mode; $V_{TXEN} = V_{IO}$	$0.4V_{BUF}$	$0.5V_{BUF}$	$0.6V_{BUF}$	V
		Standby, Go-to-sleep, Sleep, Star-standby and Star-sleep mode	-0.1	0	+0.1	V
$V_{o(idle)(BM)}$	idle output voltage on pin BM	Normal, Receive-only, Star-idle, Star-transmit and Star-receive mode; $V_{TXEN} = V_{IO}$	$0.4V_{BUF}$	$0.5V_{BUF}$	$0.6V_{BUF}$	V
		Standby, Go-to-sleep, Sleep, Star-standby and Star-sleep mode	-0.1	0	+0.1	V
$I_{o(idle)BP}$	idle output current on pin BP	$-60\text{ V} < V_{BP} < +60\text{ V}$	1	-	7.5	mA

Table 14. Static characteristics ...continued

All parameters are guaranteed for $V_{BAT} = 6.5\text{ V}$ to 60 V ; $V_{CC} = 4.75\text{ V}$ to 5.25 V ; $V_{BUF} = 4.75\text{ V}$ to 5.25 V ; $V_{IO} = 2.2\text{ V}$ to 5.25 V ; $T_{vj} = -40\text{ }^{\circ}\text{C}$ to $+150\text{ }^{\circ}\text{C}$; $R_{bus} = 45\text{ }\Omega$; $R_{TRXD} = 200\text{ }\Omega$ unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.^{[1][2]}

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$I_{O(idle)BM}$	idle output current on pin BM	$-60\text{ V} < V_{BM} < +60\text{ V}$	1	-	7.5	mA
$V_{O(idle)(dif)}$	differential idle output voltage		-25	0	+25	mV
$V_{OH(dif)}$	differential HIGH-level output voltage	$40\text{ }\Omega < R_{bus} < 55\text{ }\Omega$; $V_{CC} = V_{BUF} = 5\text{ V}$	600	800	1200	mV
$V_{OL(dif)}$	differential LOW-level output voltage	$40\text{ }\Omega < R_{bus} < 55\text{ }\Omega$; $V_{CC} = V_{BUF} = 5\text{ V}$	-1200	-800	-600	mV
$V_{IH(dif)}$	differential HIGH-level input voltage	normal power modes; $-10\text{ V} < V_{BP} < +15\text{ V}$; $-10\text{ V} < V_{BM} < +15\text{ V}$	150	225	300	mV
$V_{IL(dif)}$	differential LOW-level input voltage	normal power modes; $-10\text{ V} < V_{BP} < +15\text{ V}$; $-10\text{ V} < V_{BM} < +15\text{ V}$	-300	-225	-150	mV
		low power modes; $-10\text{ V} < V_{BP} < +15\text{ V}$; $-10\text{ V} < V_{BM} < +15\text{ V}$	-400	-225	-125	mV
$ V_{i(dif)det(act)} $	activity detection differential input voltage (absolute value)	normal power modes	150	225	300	mV
$ I_{O(sc)(BP)} $	short-circuit output current on pin BP (absolute value)	$V_{BP} = 0\text{ V}, 60\text{ V}$	10	20	30	mA
$ I_{O(sc)(BM)} $	short-circuit output current on pin BM (absolute value)	$V_{BM} = 0\text{ V}, 60\text{ V}$	10	20	30	mA
$R_{i(BP)}$	input resistance on pin BP	idle level; $R_{bus} = \infty\text{ }\Omega$	10	20	40	k Ω
$R_{i(BM)}$	input resistance on pin BM	idle level; $R_{bus} = \infty\text{ }\Omega$	10	20	40	k Ω
$R_{i(dif)(BP-BM)}$	differential input resistance between pin BP and pin BM	idle level; $R_{bus} = \infty\text{ }\Omega$	20	40	80	k Ω
$V_{cm(bus)(DATA_0)}$	DATA_0 bus common-mode voltage	$R_{bus} = 45\text{ }\Omega$	$0.4V_{BUF}$	$0.5V_{BUF}$	$0.6V_{BUF}$	V
$V_{cm(bus)(DATA_1)}$	DATA_1 bus common-mode voltage	$R_{bus} = 45\text{ }\Omega$	$0.4V_{BUF}$	$0.5V_{BUF}$	$0.6V_{BUF}$	V
$\Delta V_{cm(bus)}$	bus common-mode voltage difference	$R_{bus} = 45\text{ }\Omega$	-25	0	+25	mV

Pin INH1

$V_{OH(INH1)}$	HIGH-level output voltage on pin INH1	$I_{INH1} = -0.2\text{ mA}$	$V_{BAT} - 0.8$	-	V_{BAT}	V
$I_{L(INH1)}$	leakage current on pin INH1	Sleep mode	-5	0	+5	μA
$I_{OL(INH1)}$	LOW-level output current on pin INH1	$V_{INH1} = 0\text{ V}$	-15	-	-	mA

Table 14. Static characteristics ...continued

All parameters are guaranteed for $V_{BAT} = 6.5\text{ V}$ to 60 V ; $V_{CC} = 4.75\text{ V}$ to 5.25 V ; $V_{BUF} = 4.75\text{ V}$ to 5.25 V ; $V_{IO} = 2.2\text{ V}$ to 5.25 V ; $T_{vj} = -40\text{ }^{\circ}\text{C}$ to $+150\text{ }^{\circ}\text{C}$; $R_{bus} = 45\text{ }\Omega$; $R_{TRXD} = 200\text{ }\Omega$ unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC.^{[1][2]}

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Pin INH2						
$V_{OH(INH2)}$	HIGH-level output voltage on pin INH2	$I_{INH2} = -0.2\text{ mA}$	$V_{BAT} - 0.8$	-	V_{BAT}	V
$I_{L(INH2)}$	leakage current on pin INH2	Sleep mode	-5	0	+5	μA
$I_{OL(INH2)}$	LOW-level output current on pin INH2	$V_{INH2} = 0\text{ V}$	-15	-	-	mA
Pin WAKE						
$V_{th(det)(WAKE)}$	detection threshold voltage on pin WAKE	low power mode	2.5	-	4.5	V
$I_{IL(WAKE)}$	LOW-level input current on pin WAKE	$V_{WAKE} = 2.4\text{ V}$ for $t > t_{wake(WAKE)}$	3	-	11	μA
$I_{IH(WAKE)}$	HIGH-level input current on pin WAKE	$V_{WAKE} = 4.6\text{ V}$ for $t > t_{wake(WAKE)}$	-11	-	-3	μA
Temperature protection						
$T_{j(warn)(medium)}$	medium warning junction temperature		155	165	175	$^{\circ}\text{C}$
$T_{j(dis)(high)}$	high disable junction temperature		180	190	200	$^{\circ}\text{C}$

- [1] All parameters are guaranteed over the virtual junction temperature range by design, but only 100 % are tested at $125\text{ }^{\circ}\text{C}$ for dies on wafer level (pre-testing) and above this for cased products 100 % are tested at $T_{amb} = -40\text{ }^{\circ}\text{C}$ and $+25\text{ }^{\circ}\text{C}$ (final testing) unless otherwise specified. Both pre-testing and final testing use correlated test conditions to cover the specified temperature and power supply voltage range. For bare dies all parameters are only guaranteed with the backside of the bare die connected to ground.
- [2] At power-up V_{BAT} should be supplied first. When V_{BAT} reaches 6.5 V , V_{CC} and V_{IO} may be switched on with a delay of at least $60\text{ }\mu\text{s}$ with respect to V_{BAT} .
- [3] Current flows from V_{CC} to V_{BUF} . This means that the maximum sum current $I_{CC} + I_{BUF}$ is 35 mA .

11. Dynamic characteristics

Table 15. Dynamic characteristics

All parameters are guaranteed for $V_{BAT} = 6.5\text{ V}$ to 60 V ; $V_{CC} = 4.75\text{ V}$ to 5.25 V ; $V_{BUF} = 4.75\text{ V}$ to 5.25 V ; $V_{IO} = 2.2\text{ V}$ to 5.25 V ; $T_{vj} = -40\text{ }^{\circ}\text{C}$ to $+150\text{ }^{\circ}\text{C}$; $R_{bus} = 45\text{ }\Omega$; $R_{TRXD} = 200\text{ }\Omega$ unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC^[1].

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Pins BP and BM						
$t_{d(TXD-bus)}$	delay time from TXD to bus	Normal or Star-transmit mode	[2]			
		DATA_0	-	-	50	ns
		DATA_1	-	-	50	ns
$\Delta t_{d(TXD-bus)}$	delay time difference from TXD to bus	Normal or Star-transmit mode; between DATA_0 and DATA_1	[2]	-	4	ns
$t_{d(TRXD-bus)}$	delay time from TRXD to bus	Star-transmit mode	[3]			
		DATA_0	-	-	50	ns
		DATA_1	-	-	50	ns
$\Delta t_{d(TRXD-bus)}$	delay time difference from TRXD to bus	Star-transmit mode; between DATA_0 and DATA_1	[3][4]	-	5	ns
$t_{d(bus-RXD)}$	delay time from bus to RXD	Normal or Star-transmit mode; $C_{RXD} = 15\text{ pF}$; see Figure 11				
		DATA_0	-	-	50	ns
		DATA_1	-	-	50	ns
$\Delta t_{d(bus-RXD)}$	delay time difference from bus to RXD	Normal or Star-transmit mode; $C_{RXD} = 15\text{ pF}$; between DATA_0 and DATA_1; see Figure 11	-	-	5	ns
$t_{d(bus-TRXD)}$	delay time from bus to TRXD	Star-receive mode; see Figure 11				
		DATA_0	-	-	50	ns
		DATA_1	-	-	50	ns
$\Delta t_{d(bus-TRXD)}$	delay time difference from bus to TRXD	Star-receive mode; between DATA_0 and DATA_1; see Figure 11	[4]	-	5	ns
$t_{d(TXEN-busidle)}$	delay time from TXEN to bus idle	Normal mode	-	-	50	ns
$t_{d(TXEN-busact)}$	delay time from TXEN to bus active	Normal mode	-	-	50	ns
$t_{d(BGE-busidle)}$	delay time from BGE to bus idle	Normal mode	-	-	50	ns
$t_{d(BGE-busact)}$	delay time from BGE to bus active	Normal mode	-	-	50	ns
$t_{r(dif)(bus)}$	bus differential rise time	10 % to 90 %; $R_L = 45\text{ }\Omega$; $C_L = 100\text{ pF}$	8	12	23	ns
$t_{f(dif)(bus)}$	bus differential fall time	90 % to 10 %; $R_L = 45\text{ }\Omega$; $C_L = 100\text{ pF}$	8	12	23	ns

Table 15. Dynamic characteristics ...continued

All parameters are guaranteed for $V_{BAT} = 6.5\text{ V to }60\text{ V}$; $V_{CC} = 4.75\text{ V to }5.25\text{ V}$; $V_{BUF} = 4.75\text{ V to }5.25\text{ V}$; $V_{IO} = 2.2\text{ V to }5.25\text{ V}$; $T_{vj} = -40\text{ }^{\circ}\text{C to }+150\text{ }^{\circ}\text{C}$; $R_{bus} = 45\text{ }\Omega$; $R_{TRXD} = 200\text{ }\Omega$ unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC^[1].

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
WAKE symbol detection						
t _{det(wake)DATA_0}	DATA_0 wake-up detection time	Standby, Sleep, Star-standby or Star-sleep mode; −10 V < V _{BP} < +15 V; −10 V < V _{BM} < +15 V	1	-	4	μs
t _{det(wake)idle}	idle wake-up detection time		1	-	4	μs
t _{det(wake)tot}	total wake-up detection time		50	-	115	μs
Undervoltage						
t _{det(uv)(VCC)}	undervoltage detection time on pin V _{CC}		100	-	670	ms
t _{rec(uv)(VCC)}	undervoltage recovery time on pin V _{CC}		1	-	5.2	ms
t _{det(uv)(VIO)}	undervoltage detection time on pin V _{IO}		100	-	670	ms
t _{to(uv)(VCC)}	undervoltage time-out time on pin V _{CC} for entering Standby mode	star configuration; wake flag is set	432	-	900	μs
Activity detection						
t _{det(act)(TXEN)}	activity detection time on pin TXEN	star configuration	100	-	200	ns
t _{det(act)(TRXD)}	activity detection time on pin TRXD	star configuration	100	-	200	ns
t _{det(act)(bus)}	activity detection time on bus pins	V _{dif} : 0 mV → 400 mV	100	-	250	ns
t _{det(idle)(TXEN)}	idle detection time on pin TXEN	star configuration	100	-	200	ns
t _{det(idle)(TRXD)}	idle detection time on pin TRXD	star configuration	50	-	100	ns
t _{det(idle)(bus)}	idle detection time on bus pins	V _{dif} : 400 mV → 0 mV	100	-	250	ns
Star modes						
t _{to(idle-sleep)}	idle to sleep time-out time		640	-	2660	ms
t _{to(tx-locked)}	transmit to locked time-out time		2600	-	10400	μs
t _{to(rx-locked)}	receive to locked time-out time		2600	-	10400	μs
t _{to(locked-sleep)}	locked to sleep time-out time		64	-	333	ms
t _{to(locked-idle)}	locked to idle time-out time		1.4	-	5.1	μs
Node modes						
t _{d(STBN-RXD)}	STBN to RXD delay time	wake flag set	-	-	2	μs
t _{d(STBN-INH2)}	STBN to INH2 delay time		-	-	10	μs
t _{h(gotosleep)}	go-to-sleep hold time		20	35	50	μs
Status register						
t _{det(EN)}	detection time on pin EN	for mode control	20	-	80	μs
T _{EN}	time period on pin EN	for reading status bits	4	-	20	μs
t _{d(EN-ERRN)}	delay time from EN to ERRN	for reading status bits	-	-	2	μs

Table 15. Dynamic characteristics ...continued

All parameters are guaranteed for $V_{BAT} = 6.5\text{ V to }60\text{ V}$; $V_{CC} = 4.75\text{ V to }5.25\text{ V}$; $V_{BUF} = 4.75\text{ V to }5.25\text{ V}$; $V_{IO} = 2.2\text{ V to }5.25\text{ V}$; $T_{vj} = -40\text{ }^{\circ}\text{C to }+150\text{ }^{\circ}\text{C}$; $R_{bus} = 45\text{ }\Omega$; $R_{TRXD} = 200\text{ }\Omega$ unless otherwise specified. All voltages are defined with respect to ground; positive currents flow into the IC^[1].

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
WAKE						
$t_{wake(WAKE)}$	wake-up time on pin WAKE	low power mode; falling edge on pin WAKE; $6.5\text{ V} < V_{BAT} < 27\text{ V}$	5	25	100	μs
		low power mode; falling edge on pin WAKE; $27\text{ V} < V_{BAT} < 60\text{ V}$	25	75	175	μs
Miscellaneous						
$t_{detCL(TXEN_BGE)}$	TXEN_BGE clamp detection time		2600	-	10400	μs

- [1] At power-up V_{BAT} should be supplied first. When V_{BAT} reaches 6.5 V, V_{CC} and V_{IO} may be switched on with a delay of at least 60 μs with respect to V_{BAT} .
- [2] Rise and fall time (10 % to 90 %) of $t_{r(TXD)}$ and $t_{f(TXD)} = 5\text{ ns}$.
- [3] Rise and fall time (10 % to 90 %) of $t_{r(TRXD)}$ and $t_{f(TRXD)} = 5\text{ ns}$.
- [4] The worst case asymmetry from one branch to another is the sum of the delay difference from TRXD0 and TRXD1 to DATA_0 and DATA_1 plus the delay difference from DATA_0 and DATA_1 to TRXD0 and TRXD1.

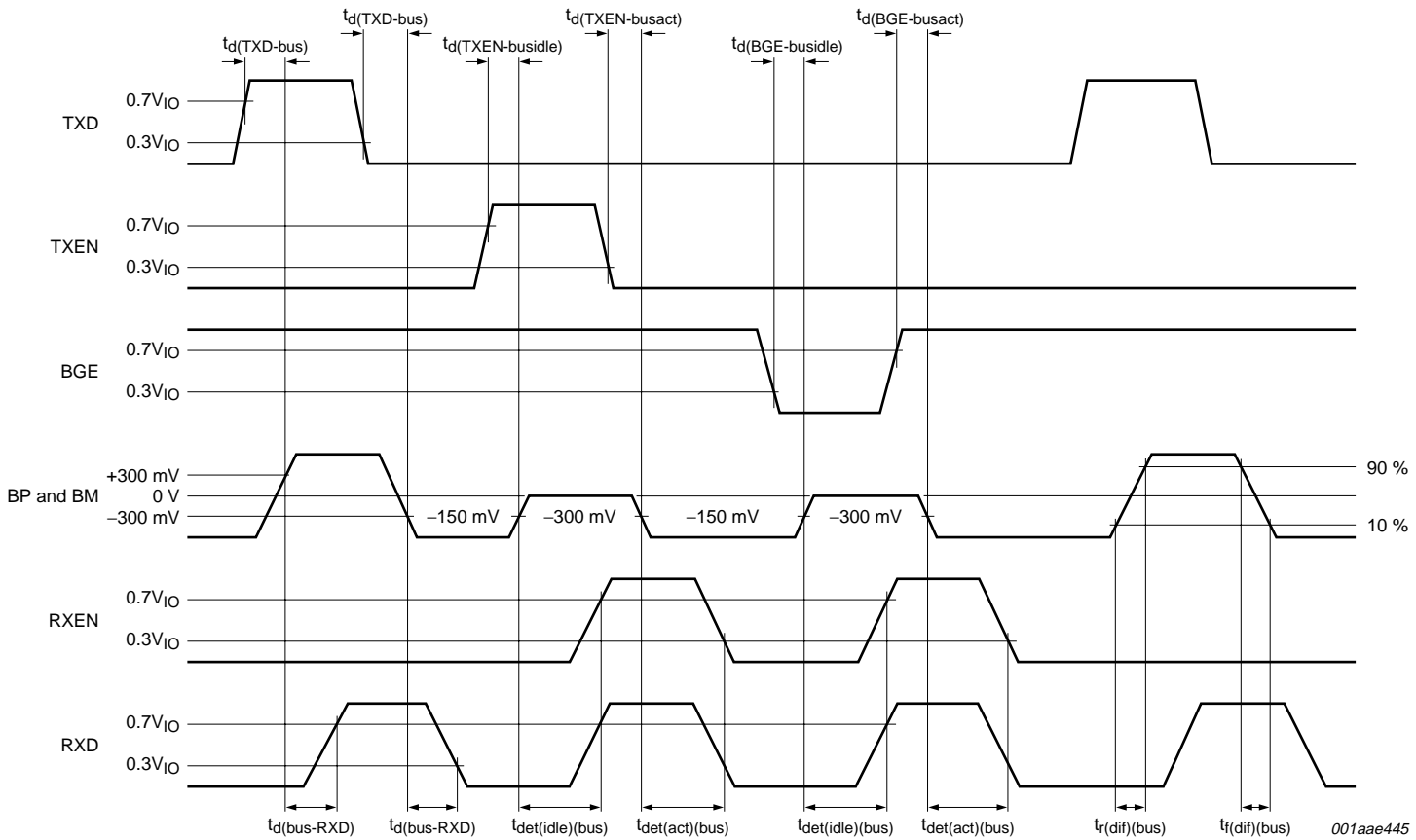
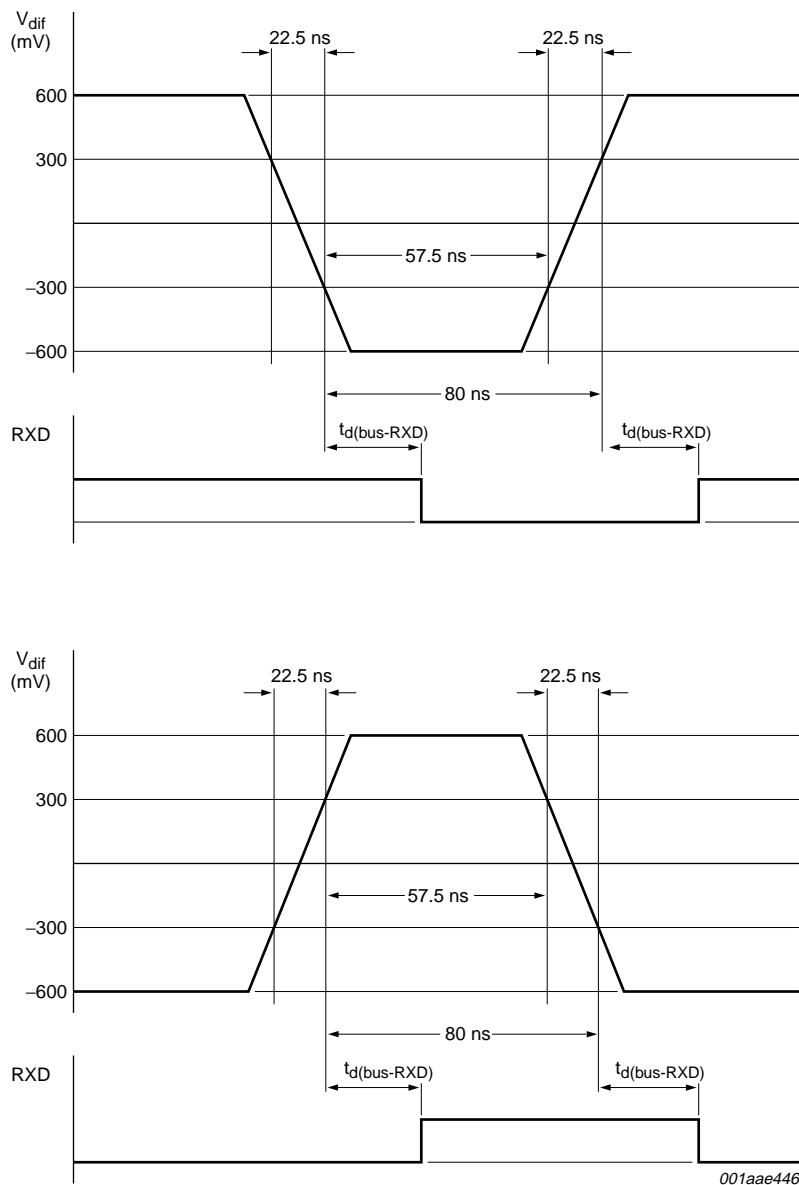


Fig 10. Detailed timing diagram in node configuration



V_{dif} is the receiver test signal.

Fig 11. Receiver test signal

12. Test information

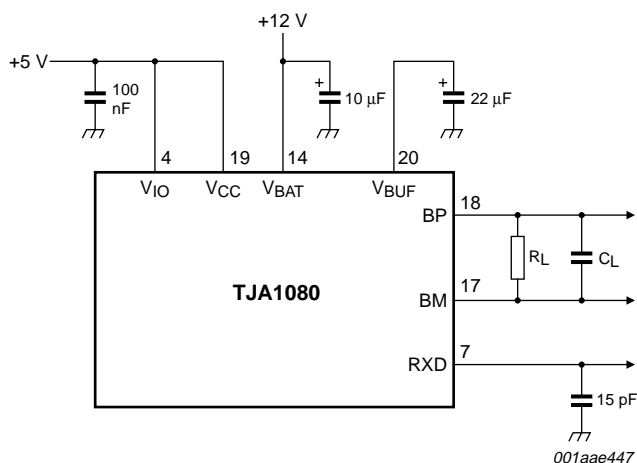
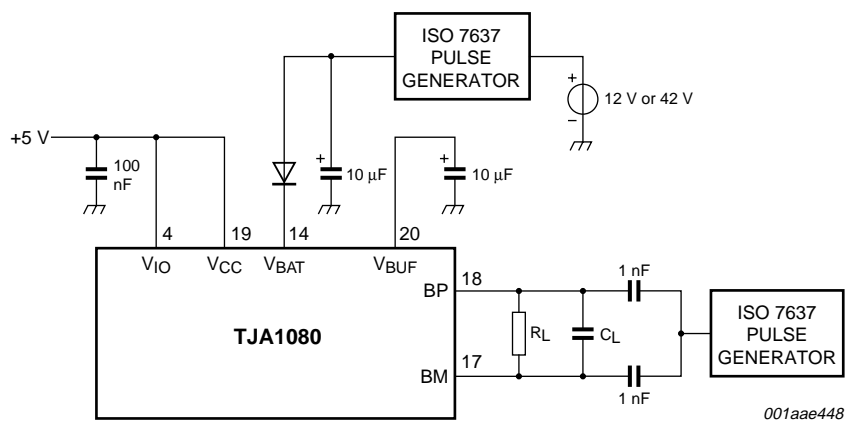


Fig 12. Test circuit for dynamic characteristics



The waveforms of the applied transients are in accordance with ISO 7637, test pulses 1, 2, 3a, 3b, 4 and 5.

Test conditions:

Normal mode: bus idle

Normal mode: bus active; TXD at 5 MHz and TXEN at 1 kHz

Fig 13. Test circuit for automotive transients

13. Package outline

SSOP20: plastic shrink small outline package; 20 leads; body width 5.3 mm SOT339-1

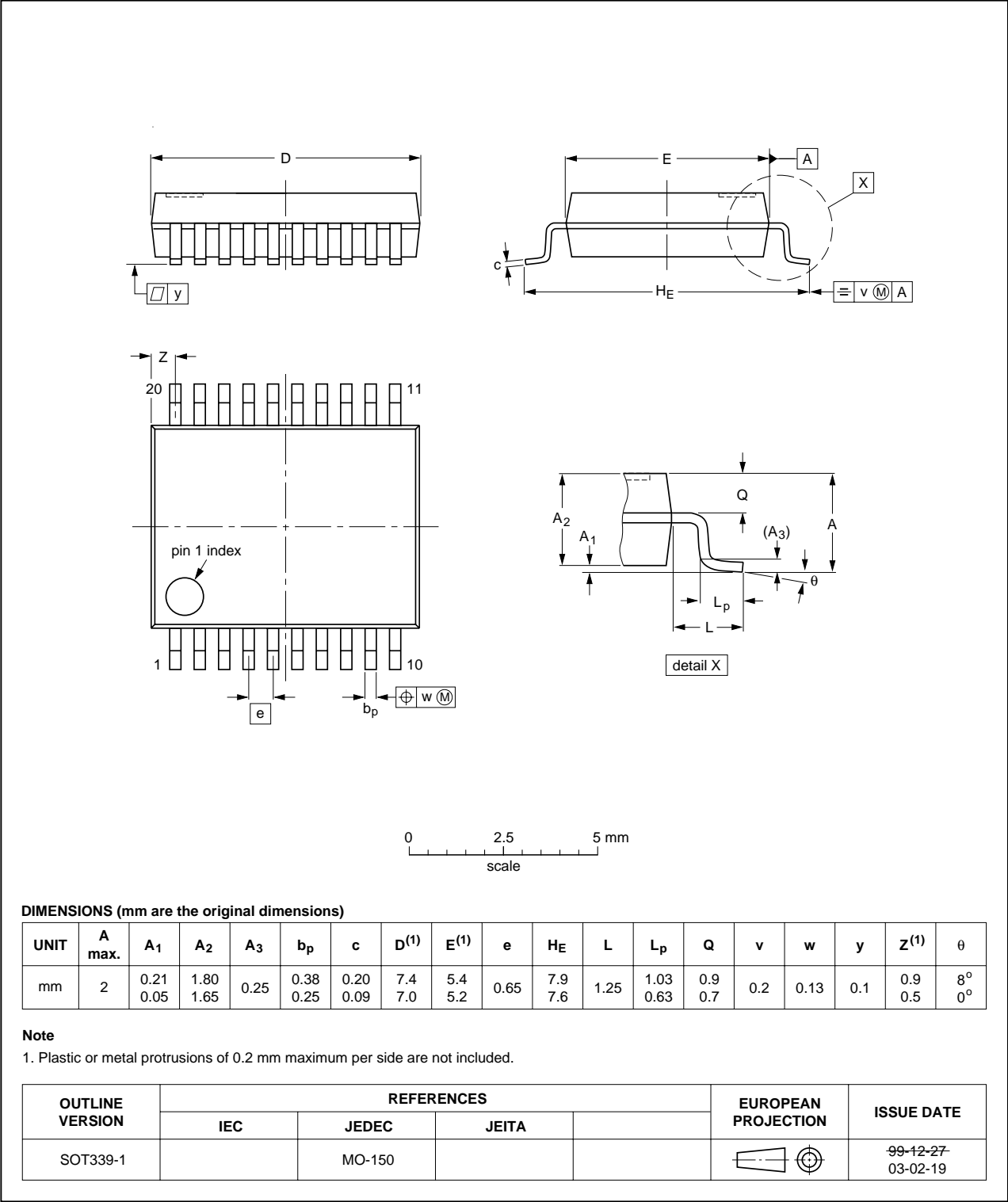


Fig 14. Package outline SOT339-1 (SSOP20)

14. Soldering

This text provides a very brief insight into a complex technology. A more in-depth account of soldering ICs can be found in Application Note *AN10365 "Surface mount reflow soldering description"*.

14.1 Introduction to soldering

Soldering is one of the most common methods through which packages are attached to Printed Circuit Boards (PCBs), to form electrical circuits. The soldered joint provides both the mechanical and the electrical connection. There is no single soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and Surface Mount Devices (SMDs) are mixed on one printed wiring board; however, it is not suitable for fine pitch SMDs. Reflow soldering is ideal for the small pitches and high densities that come with increased miniaturization.

14.2 Wave and reflow soldering

Wave soldering is a joining technology in which the joints are made by solder coming from a standing wave of liquid solder. The wave soldering process is suitable for the following:

- Through-hole components
- Leadless or leadless SMDs, which are glued to the surface of the printed circuit board

Not all SMDs can be wave soldered. Packages with solder balls, and some leadless packages which have solder lands underneath the body, cannot be wave soldered. Also, leadless SMDs with leads having a pitch smaller than ~0.6 mm cannot be wave soldered, due to an increased probability of bridging.

The reflow soldering process involves applying solder paste to a board, followed by component placement and exposure to a temperature profile. Leadless packages, packages with solder balls, and leadless packages are all reflow solderable.

Key characteristics in both wave and reflow soldering are:

- Board specifications, including the board finish, solder masks and vias
- Package footprints, including solder thieves and orientation
- The moisture sensitivity level of the packages
- Package placement
- Inspection and repair
- Lead-free soldering versus PbSn soldering

14.3 Wave soldering

Key characteristics in wave soldering are:

- Process issues, such as application of adhesive and flux, clinching of leads, board transport, the solder wave parameters, and the time during which components are exposed to the wave
- Solder bath specifications, including temperature and impurities

14.4 Reflow soldering

Key characteristics in reflow soldering are:

- Lead-free versus SnPb soldering; note that a lead-free reflow process usually leads to higher minimum peak temperatures (see [Figure 15](#)) than a PbSn process, thus reducing the process window
- Solder paste printing issues including smearing, release, and adjusting the process window for a mix of large and small components on one board
- Reflow temperature profile; this profile includes preheat, reflow (in which the board is heated to the peak temperature) and cooling down. It is imperative that the peak temperature is high enough for the solder to make reliable solder joints (a solder paste characteristic). In addition, the peak temperature must be low enough that the packages and/or boards are not damaged. The peak temperature of the package depends on package thickness and volume and is classified in accordance with [Table 16](#) and [17](#)

Table 16. SnPb eutectic process (from J-STD-020C)

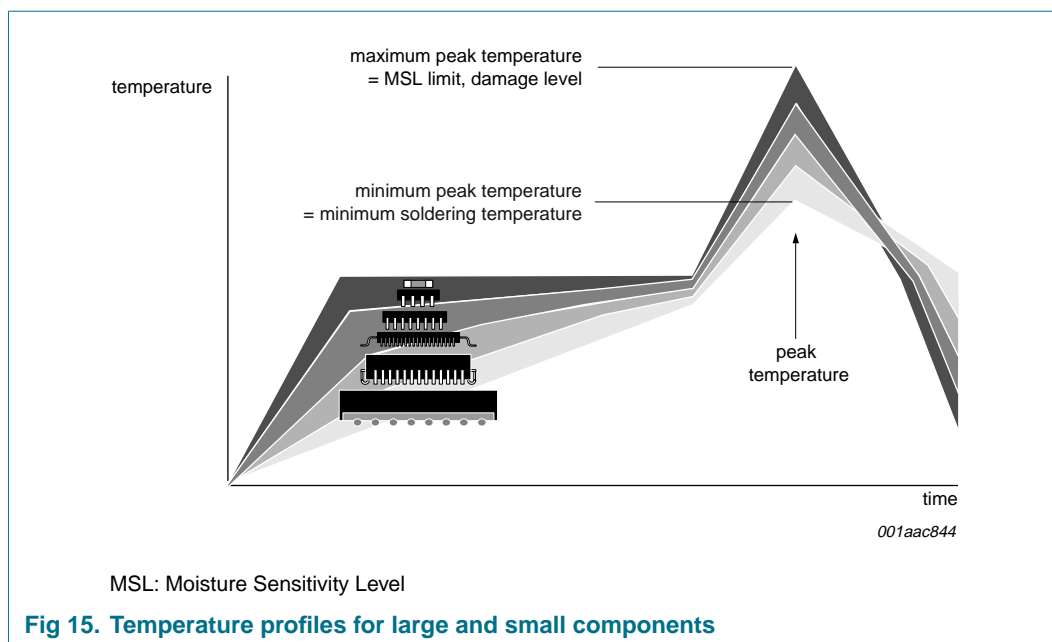
Package thickness (mm)	Package reflow temperature (°C)	
	Volume (mm ³)	
	< 350	≥ 350
< 2.5	235	220
≥ 2.5	220	220

Table 17. Lead-free process (from J-STD-020C)

Package thickness (mm)	Package reflow temperature (°C)		
	Volume (mm ³)		
	< 350	350 to 2000	> 2000
< 1.6	260	260	260
1.6 to 2.5	260	250	245
> 2.5	250	245	245

Moisture sensitivity precautions, as indicated on the packing, must be respected at all times.

Studies have shown that small packages reach higher temperatures during reflow soldering, see [Figure 15](#).



For further information on temperature profiles, refer to Application Note *AN10365* “Surface mount reflow soldering description”.

15. Appendix

15.1 Errata: known issues of the TJA1080

15.1.1 Power-up supply sequence

For proper initialization of the internal state machine the V_{BAT} voltage has to be applied first when powering-up the TJA1080. When V_{BAT} reaches 6.5 V, V_{CC} and V_{IO} may be switched on with a delay of at least 60 μ s with respect to V_{BAT} .

In case the rise time of the V_{BAT} voltage from 0 V to 6.5 V is below 10 ms, V_{CC} and V_{IO} shall be switched on with a delay time of at least 60 μ s after V_{BAT} has reached 6.5 V. In case the rise time of the V_{BAT} voltage $t_{r(VBAT)}$ is longer than 10 ms, no delayed switching of V_{CC} and V_{IO} is needed.

The rise time of the V_{CC} voltage should be below the minimum value of the V_{CC} undervoltage detection time $t_{det(uv)(VCC)}$. Otherwise, an undervoltage condition at V_{CC} would be detected and the TJA1080 would enter Standby mode. Similarly, the rise time of the V_{IO} voltage should be below the minimum value of the V_{IO} undervoltage detection time $t_{det(uv)(VIO)}$.

If the voltage on all three supply pins V_{BAT} , V_{CC} and V_{IO} of the TJA1080 drops under 4 V during a running application, the power sequence as mentioned above has to be applied again.

Consequences of an improper power-up sequence

In case of an improper initialization due to ramping up V_{BAT} and V_{CC} simultaneously, it may happen that a TJA1080 transceiver applied for star configuration may come up in node configuration.

The other way around, erroneous configuration in star configuration, while the transceiver is applied as node transceiver, has not been observed, however it is strongly recommended to apply the power-up sequence also to node transceivers.

Furthermore, due to improper initialization, it can occur that ERRN becomes clamped to permanent LOW in both node and star configuration.

Work around

There is no work around for this issue. To ensure a proper device initialization the correct power-up sequence has to be applied.

15.1.2 Bus error detection when transmitting a wake-up pattern

The TJA1080 expects a data frame that begins with a bit value different from the last bit of the previous data frame.

This is the case for a valid data frame, which begins with the DATA_0 period of the Transmission-Start-Sequence (TSS) and ends with the DATA_1 bit of the Frame-End-Sequence (FES).

Any violation of this frame format will be detected by the TJA1080. Consequently when transmitting a wake-up pattern, a bus error will be signaled.

Consequences

This behavior of the TJA1080 is not conform to the FlexRay Electrical Physical Layer specification [1]

Work around

The error indication when a wake-up pattern is transmitted should be ignored and the status register should be cleared by reading the vector.

15.1.3 Receiver signal

The delay time and delay time difference from bus to RXD (see [Table 15](#): $t_{d(bus-RXD)}$, $\Delta t_{d(bus-RXD)}$, $t_{d(bus-TRXD)}$, $\Delta t_{d(bus-TRXD)}$) is guaranteed in the TJA1080 for a minimum bit time of 80 ns and a receiver test signal of 600 mV differential bus level (see [Figure 11](#)). This receiver test signal is not conform to the FlexRay Electrical Physical Layer specification (see [Ref. 1](#)).

Consequence

If the differential bus level becomes lower than 600 mV, the delay time difference from bus to RXD ($t_{d(bus-RXD)}$) can become higher than 5 ns.

Work around

To keep the differential bus amplitude in the entire system above 600 mV, the cable impedance of the chosen bus cable shall be higher than 110 Ω . Moreover, the termination resistance at the two bus ends shall be not lower than 110 Ω .

15.1.4 Wake-up signaling via RXD pin

In case of an undervoltage condition at V_{CC} , RXD might go to LOW level.

Consequence

In case of an undervoltage condition at V_{CC} , while the TJA1080 is in a low power mode, the TJA1080 can give a continuous signaling of a wake-up event on pin RXD. This behavior is not conform to the FlexRay Electrical Physical Layer specification (see [Ref. 1](#)).

Work around

Use the RXEN pin for wake-up recognition when the V_{CC} voltage is switched off while V_{IO} is available.

16. Abbreviations**Table 18. Abbreviations**

Abbreviation	Description
CAN	Controller Area Network
CDM	Charged Device Model
EMC	ElectroMagnetic Compatibility
EME	ElectroMagnetic Emission
EMI	ElectroMagnetic Immunity
ESD	ElectroStatic Discharge
HBM	Human Body Model
MM	Machine Model
PWON	Power-on

17. References

- [1] **EPL** — FlexRay Communications System Electrical Physical Layer Specification Version 2.1 Rev. A, FlexRay Consortium, Dec. 2005
- [2] **PS54** — Product Specification: TJA1054; Fault-tolerant CAN transceiver, www.nxp.com
- [3] **PS41** — Product Specification: TJA1041; High speed CAN transceiver, www.nxp.com
- [4] **AN1** — Application hint AN10443_1; TJA1080 FlexRay transceiver

18. Revision history

Table 19. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
TJA1080_2	20070712	Product data sheet	-	TJA1080_1
Modifications:	<ul style="list-style-type: none">• The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors• Legal texts have been adapted to the new company name where appropriate• Section 4 "Ordering information", added type number TJA1080TS (lead free version)• Figure 1 and Figure 4 updated• Table 4, Table 5, Table 6, Table 7, Table 8 and Table 10 updated• Section 7.6 "Fail silent behavior", added more information• Section 15 "Appendix", added			
TJA1080_1	20060720	Objective data sheet	-	-

19. Legal information

19.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

19.2 Definitions

Draft — The document is a draft version only. The content is still under internal review and subject to formal approval, which may result in modifications or additions. NXP Semiconductors does not give any representations or warranties as to the accuracy or completeness of information included herein and shall have no liability for the consequences of use of such information.

Short data sheet — A short data sheet is an extract from a full data sheet with the same product type number(s) and title. A short data sheet is intended for quick reference only and should not be relied upon to contain detailed and full information. For detailed and full information see the relevant full data sheet, which is available on request via the local NXP Semiconductors sales office. In case of any inconsistency or conflict with the short data sheet, the full data sheet shall prevail.

19.3 Disclaimers

General — Information in this document is believed to be accurate and reliable. However, NXP Semiconductors does not give any representations or warranties, expressed or implied, as to the accuracy or completeness of such information and shall have no liability for the consequences of use of such information.

Right to make changes — NXP Semiconductors reserves the right to make changes to information published in this document, including without limitation specifications and product descriptions, at any time and without notice. This document supersedes and replaces all information supplied prior to the publication hereof.

Suitability for use — NXP Semiconductors products are not designed, authorized or warranted to be suitable for use in medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customer's own risk.

Applications — Applications that are described herein for any of these products are for illustrative purposes only. NXP Semiconductors makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

Limiting values — Stress above one or more limiting values (as defined in the Absolute Maximum Ratings System of IEC 60134) may cause permanent damage to the device. Limiting values are stress ratings only and operation of

the device at these or any other conditions above those given in the Characteristics sections of this document is not implied. Exposure to limiting values for extended periods may affect device reliability.

Terms and conditions of sale — NXP Semiconductors products are sold subject to the general terms and conditions of commercial sale, as published at <http://www.nxp.com/profile/terms>, including those pertaining to warranty, intellectual property rights infringement and limitation of liability, unless explicitly otherwise agreed to in writing by NXP Semiconductors. In case of any inconsistency or conflict between information in this document and such terms and conditions, the latter will prevail.

No offer to sell or license — Nothing in this document may be interpreted or construed as an offer to sell products that is open for acceptance or the grant, conveyance or implication of any license under any copyrights, patents or other industrial or intellectual property rights.

Suitability for use in automotive applications only — This NXP Semiconductors product has been developed for use in automotive applications only. The product is not designed, authorized or warranted to be suitable for any other use, including medical, military, aircraft, space or life support equipment, nor in applications where failure or malfunction of an NXP Semiconductors product can reasonably be expected to result in personal injury, death or severe property or environmental damage. NXP Semiconductors accepts no liability for inclusion and/or use of NXP Semiconductors products in such equipment or applications and therefore such inclusion and/or use is at the customers own risk.

19.4 Licenses

Purchase of NXP ICs with FlexRay functionality

FlexRay license required. This product has been developed within the framework of the "FlexRay" consortium. FlexRay consortium members are willing to grant licenses under their essential FlexRay intellectual property rights to end users of FlexRay-enabled products upon request of an end user. The sale by NXP Semiconductors of a FlexRay-enabled product will not be construed as the granting of such a license. Each end user will have to apply to the FlexRay consortium administration to obtain such a license or to apply for membership. The FlexRay consortium can be contacted at request@flexray.com.

19.5 Trademarks

Notice: All referenced brands, product names, service names and trademarks are the property of their respective owners.

20. Contact information

For additional information, please visit: <http://www.nxp.com>

For sales office addresses, send an email to: salesaddresses@nxp.com

21. Contents

1	General description	1	7.7.4	Power-on flag	23
2	Features	1	7.7.5	Node configuration flag	23
2.1	Optimized for time triggered communication systems.	1	7.7.6	Temperature medium flag	23
2.2	Low power management	2	7.7.7	Temperature high flag	23
2.3	Diagnosis (detection and signalling)	2	7.7.8	TXEN_BGE clamped flag.	23
2.4	Protections	2	7.7.9	Bus error flag	24
3	Quick reference data	2	7.7.10	UV _{V_{BAT}} flag.	24
4	Ordering information	3	7.7.11	UV _{V_{CC}} flag	24
5	Block diagram	4	7.7.12	UV _{V_{IO}} flag	24
6	Pinning information	5	7.7.13	Error flag	24
6.1	Pinning	5	7.8	TRXD collision	24
6.2	Pin description	5	7.9	Status register	24
7	Functional description	6	8	Limiting values	26
7.1	Operating configurations.	6	9	Thermal characteristics	27
7.1.1	Node configuration	6	10	Static characteristics	27
7.1.2	Star configuration	6	11	Dynamic characteristics	33
7.1.3	Bus activity and idle detection	7	12	Test information	38
7.2	Operating modes in node configuration	7	13	Package outline	39
7.2.1	Normal mode	14	14	Soldering	40
7.2.2	Receive-only mode	14	14.1	Introduction to soldering.	40
7.2.3	Standby mode.	14	14.2	Wave and reflow soldering	40
7.2.4	Go-to-sleep mode.	14	14.3	Wave soldering.	40
7.2.5	Sleep mode.	15	14.4	Reflow soldering.	41
7.3	Operating modes in star configuration	15	15	Appendix	42
7.3.1	Star-idle mode	17	15.1	Errata: known issues of the TJA1080.	42
7.3.2	Star-transmit mode	18	15.1.1	Power-up supply sequence	42
7.3.3	Star-receive mode	18	15.1.2	Bus error detection when transmitting a wake-up pattern	43
7.3.4	Star-standby mode	18	15.1.3	Receiver signal.	43
7.3.5	Star-sleep mode	19	15.1.4	Wake-up signaling via RXD pin	44
7.3.6	Star-locked mode	19	16	Abbreviations	44
7.4	Start-up.	19	17	References	44
7.4.1	Node configuration	19	18	Revision history	45
7.4.2	Star configuration	19	19	Legal information	46
7.5	Wake-up mechanism	20	19.1	Data sheet status	46
7.5.1	Node configuration	20	19.2	Definitions	46
7.5.2	Star configuration	20	19.3	Disclaimers.	46
7.5.3	Bus wake-up	20	19.4	Licenses	46
7.5.4	Local wake-up via pin WAKE	21	19.5	Trademarks	46
7.6	Fail silent behavior	21	20	Contact information	47
7.6.1	V _{BAT} undervoltage.	22	21	Contents	48
7.6.2	V _{CC} undervoltage	22			
7.6.3	V _{IO} undervoltage.	22			
7.7	Flags.	22			
7.7.1	Local wake-up source flag	22			
7.7.2	Remote wake-up source flag	22			
7.7.3	Wake flag	23			

Please be aware that important notices concerning this document and the product(s) described herein, have been included in section 'Legal information'.

founded by

PHILIPS

© NXP B.V. 2007.

All rights reserved.

For more information, please visit: <http://www.nxp.com>For sales office addresses, please send an email to: salesaddresses@nxp.com

Date of release: 12 July 2007

Document identifier: TJA1080_2